ASMA Ver.	0.7.0 zvector-e7-0	6-Find (Zv	ector E7 V	RR-a i	nstructi	on)		14 Feb 2025 21: 40: 22 Page 3
LOC	OBJECT CODE	ADDR1	ADDR2	STM				
				108			**************************************	*********
00000000		00000000 00000000	0000438F			START USI NG	0 ZVE7TST, RO	Low core addressability
		00000140	00000000		SVOLDPSW	EQU	ZVE7TST+X' 140'	z/Arch Supervisor call old PSW
	00000001 80000000	00000000	000001A0	115 116		ORG DC	ZVE7TST+X' 1A0' X' 00000001800000	z/Architecure RESTART PSW 00'
000001A8	00000000 00000200			117		DC	AD(BEGIN)	
	00020001 80000000 00000000 0000DEAD	000001B0	000001D0	119 120 121		ORG DC DC	ZVE7TST+X' 1D0' X' 00020001800000 AD(X' DEAD')	z/Architecure PROGRAM CHECK PSW 00'
000001E0		000001E0	00000200	123		ORG	ZVE7TST+X' 200'	Start of actual test program
					*****	****** ****	**************************************	**************************************
				128 129 130	* Archit * Regist	tecture ter Usa	e Mode: z/Arch age:	
				131 132 133	* R0 * R1-4	()	work) work)	
				134 135 136	* R6-R 7	7 (1	esting control ta work) irst base registe	ble - current test base r
				137 138 139	* R9 * R10	So Tl	econd base regist hird base registe 7TEST call return	er r
				140 141 142	* R12 * R13	E′.	7TESTS register work) ubroutine call	
				143 144 145	* R15		econdary Subrouti	ne call or work ***********************************
00000200 00000200 00000200		00000200 00001200 00002200		147 148 149		USING	BEGIN, R8 BEGIN+4096, R9 BEGIN+8192, R10	FIRST Base Register SECOND Base Register THIRD Base Register
00000200	0580	3000mm00		151	BEGI N	BALR	R8, 0	Initalize FIRST base register
	0680			152 153		BCTR BCTR	R8, 0	Initalize FIRST base register Initalize FIRST base register
	4190 8800 4190 9800		00000800 00000800	155 156 157		LA LA	R9, 2048(, R8) R9, 2048(, R9)	Initalize SECOND base register Initalize SECOND base register

ASMA Ver.	0. 7. 0 zvector-e7-0	6- Find (Zv	ector E7 V	RR-a instruction	on)		14 Feb 2025 21: 40: 22 Page 4
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
0000020E 00000212	41A0 9800 41A0 A800		00000800 00000800	158 159	LA LA	R10, 2048(, R9) R10, 2048(, R10)	Initalize THIRD base register Initalize THIRD base register
00000216 0000021A	B600 8354 9604 8355		00000554 00000555	160 161 162	$\mathbf{0I}$	CTLR0+1, X' 04'	Store CRO to enable AFP Turn on AFP bit
0000021E 00000222	9602 8355 B700 8354		00000555 00000554	163 164 165		RO, RO, CTLRO	Turn on Vector bit Reload updated CRO
				167 * Is z/Ai 168 ******			ity installed (bit 129) ***********************************
00000226	47F0 80A8		000002A8	169 170 171+	FCHECE B	K 129, 'z/Archi tect X0001	cure vector facility'
0000022A	40404040 E2928997			172+* 173+* 174+SKT0001	DC	C' Skipping te	Fcheck data area skip messgae ests: '
0000023E 0000025C	A961C199 838889A3 404D8289 A340F1F2	0000004E	00000001	175+ 176+ 177+SKL0001	DC DC EQU	C'z/Architecture C' (bit 129) is n *-SKT0001	vector facility'
00000278 00000280	00000000 00000000 00000000 00000000			178+* 179+ 180+FB0001	DS DS	FD 4FD	facility bits gap
000002A0	00000000 00000000	000002A8	00000001	181+ 182+* 183+X0001	DS EQU	FD *	gap
000002A8 000002AC 000002B0	4100 0004 B2B0 8080 B982 0000	OOOOO	00000004 00000280	184+ 185+ 186+	LÀ	RO, ((X0001-FB0001 FB0001 RO, RO)/8)-1 get facility bits
000002B4 000002B8 000002BC	4300 8090 5400 8368 4770 80D0		00000290 00000568 000002D0	187+ 188+ 189+	I C N BNZ	RO, FB0001+16 RO, =F' 64' XC0001	get fbit byte is bit set?
				190+*		not set, issue me	essage and exit
000002C0 000002C4 000002C8	4100 004E 4110 802A 4520 8270		0000004E 0000022A 00000470	193+ 194+ 195+	LA LA BAL	RO, SKL0001 R1, SKT0001 R2, MSG	message length message address
000002CC	47F0 8338	000002D0	$00000538 \\ 00000001$	196+ 197+XC0001	B EQU	E0J	

EOJ

FAILTEST

No. exit

Yes, exit with BAD PSW

BZ

4780 8338

47F0 8350

0000042E

00000432

00000538

00000550

333

ASMA Ver.	0. 7. 0 zvector- e7- 0	6-Find (Zvec	tor E7 V	RR-a i	nstructi	on)		14 Feb 2025 21: 40: 22 Page
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				

				337 338		RPTER		instruction test in error MESSGAE LENGTH
				339				ADDRESS OF MESSAGE
						*****		**********
0000436 000043A	50F0 8254 5050 8258		0000454 0000458	342 343	RPTERROR	ST ST	R15, RPTSAVE R5, RPTSVR5	Save return address Save R5
00001011		·		344 345 346	*		ercules Diagnose for	
000043E	9002 8260	0	0000460	347		STM	RO, R2, RPTDWSAV	save regs used by MSG
0000442	4520 8270		0000470	348		BAL	R2, MSG	call Hercules console MSG display
0000446	9802 8260	0	0000460	349		LM	RO, R2, RPTDWSAV	restore regs
000044A	5850 8258	0	0000458	351		L	R5, RPTSVR5	Restore R5
000044E	58F0 8254		0000454	352		L	R15, RPTSAVE	Restore return address
0000452	07FF			353		BR	R15	Return to caller
0000454	00000000					DC	F' 0'	R15 save area
0000458	0000000			356	RPTSVR5	DC	F' 0'	R5 save area
0000460	00000000 00000000			358	RPTDWSAV	DC	2D' 0'	RO-R2 save area for MSG call
				361 362	*	Issue	HERCULES MESSAGE po R2 = return address	**************************************
0000470	4900 8378	0	0000578	265	MCC	CII	DΩ _U'Ω'	Do we even HAVE a magazage?
0000470 0000474		U	0000378	366	MSG	CH BNHR	RO, =H' O' R2	Do we even HAVE a message? No, ignore
0000476	9002 82AC	0	00004AC	368		STM	RO, R2, MSGSAVE	Save registers
000047A	4900 837A	0	000057A	370		СН	RO, =AL2(L' MSGMSG)	Message length within limits?
000047E	47D0 8286	0	0000486	371		BNH	MSGOK	Yes, continue
0000482	4100 005F	0	000005F	372		LA	RO, L' MSGMSG	No, set to maximum
0000486	1820				MSGOK	LR	R2, R0	Copy length to work register
0000488 000048A	0620 4420 82B8	0	00004B8	375 376		BCTR EX	R2, 0 R2, MSGMVC	Minus-1 for execute Copy message to O/P buffer
000048E 0000492	4120 200A 4110 82BE		000000A 00004BE	378 379		LA LA	R2, 1+L' MSGCMD(, R2) R1, MSGCMD	Calculate true command length Point to true command
0000496 000049A	83120008 4780 82A6	0	00004A6	381 382 383		DC BZ	X' 83', X' 12', X' 0008' MSGRET	Issue Hercules Diagnose X'008' Return if successful
000049E 00004A0	1222 4780 82A6	0	00004A6	384 385 386		LTR BZ	R2, R2 MSGRET	Is Diag8 Ry (R2) 0? an error occurred but coninue
00004A4	0000			387		DC	Н' О'	CRASH for debugging purposes
00004A6	9802 82AC	0	00004AC	389	MSGRET	LM	RO, R2, MSGSAVE	Restore registers
								<u> </u>

ASMA Ver.	0. 7. 0 zvector- e7- 0	6-Find (Zv	ector E7	VRR-a instructi	on)		14 Feb 2025 21: 40: 22 Page 9
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
000004AA	07F2			390	BR	R2	Return to caller
	00000000 00000000			392 MSGSAVE	DC	3F' 0'	Registers save area Executed instruction
000004B8	D200 82C7 1000	000004C7	00000000	393 MSGMVC	MVC	MSGMSG(0), 0(R1)	Executed instruction
000004BE 000004C7	D4E2C7D5 D6C8405C 40404040 40404040			395 MSGCMD 396 MSGMSG 397	DC DC	C' MSGNOH * ' CL95' '	*** HERCULES MESSAGE COMMAND *** The message text to be displayed

ASMA Ver.	0.7.0 zvector-e7-0	6-Find (Zv	ector E7	VRR-a i	nstructi	on)		14 Feb 2025 21: 40: 22 Page 10
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
				399 400 401	******* * ******	****** Normal *****		**************************************
00000528	00020001 80000000			403	E0JPSW	DC	OD' O' , X' 000200018000000	00', AD(0)
00000538	B2B2 8328		00000528	405	ЕОЈ	LPSWE	EOJPSW	Normal completion
00000540	00020001 80000000			407	FAI LPSW	DC	OD' O' , X' 000200018000000	00', AD(X'BAD')
00000550	B2B2 8340		00000540	409	FAILTEST	LPSWE	FAILPSW	Abnormal termination
				411 412 413	****** * ******			**************************************
00000554 00000558	00000000 00000000			415 416	CTLRO	DS DS	F F	CRO
00000568	00000000 00000001 00000040			418 419 420		LTORG	=D' 1' =F' 64'	Literals pool
0000056C 00000570 00000574				421 422 423			=A(E7TESTS) =XL4'3' =F'1'	
00000578 0000057A				424 425 426			=H' 0' =AL2(L' MSGMSG)	
				427 428	*	some o	constants	
		00000400	00000001	429		EQU	1024	One KB
		00001000 00010000 00100000	$\begin{array}{c} 00000001 \\ 00000001 \\ 00000001 \end{array}$	431 432		EQU EQU EQU	(4*K) (64*K) (K*K)	Size of one page 64 KB 1 MB
		AABBCCDD 000000DD	00000001 00000001		REG2PATT REG2LOW		X' AABBCCDD' X' DD'	Polluted Register pattern (last byte above)

ASMA Ver.	0. 7. 0 zvector- e7-	06-Find (Zvector E7	VRR-a	instructi	on)		14 Feb 2025 21: 40: 22 Pag	e 12
LOC	OBJECT CODE	ADDR1 ADDR2	STM					
			484	*****	*****	******	************	*
			485	*	TEST 1	failed : messag	e working storge ************************************	st.
000010AA	40212020 20202020			EDIT	DC		02	*
000010BC	7E7E7E6E		489		DC	C' ===>'		
000010C0 000010D2	40404040 40404040 4C7E7E7E		490 491	PRT3	DC DC	CL18' ' C' <==='		
	00000000 00000000			DECNUM	DS	CL16		
			494	*****	****	******	*************	*
			495	* * * * * * * * *	Vector	r instruction r	esults, pollution and input ************************************	*
000010E8			496 497		DS	OF		··
000010E8	00000000 00000000		498	V4 EUDCE	DS	XL16	gap FFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFF	
000010F8 00001108	FFFFFFF FFFFFFF 00000000 00000000		499 500	V1FUDGE	DC DS	XL16 FFFFFFFF XL16	FFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFF	
			502				************	*
			503 504	*****		Γ DSECT *************	************	*
00000000	0000000			E7TEST TSUB	DSECT DC	, A(0)	nointan to tost	
00000000	0000			TNUM	DC DC	H' 00'	pointer to test Test Number	
00000006 00000007	00		509 510	MD	DC DC	X' 00' HL1' 00'	MD wood	
00000007	00 00		510		DC DC	HL1' 00'	MB used M5 used	
00000009	00		512		DC	HL1' 00'	cc expected	
000000A	00		513 514	CCMASK *	DC	HL1' 00'	not expected CC mask	
			515	*	CC ext	trtacti on		
000000C	0000000 00000000		516 517	* CCPSW	DS	2F	extract PSW after test (has CC)	
00000014			518	CCFOUND	DS	X	extracted cc	
00000015	40404040 40404040		519 520	OPNAME	DC	CL8' '	E7 name	
0000020	0000000		521	V1ADDR	DC	A(0)	address of v1 result	
00000024 00000028	00000000 0000000			V2ADDR V3ADDR	DC DC	A(0) A(0)	address of v2 source address of v3 source	
	0000000			RELEN	DC	A(0) A(0)	RESULT LENGTH	
00000030	0000000		525	READDR	DC	A(0)	result (expected) address	
	0000000 0000000 0000000 0000000		526 527	V10UTPUT	DS DS	FD XL16	gap V1 Output	
	00000000 00000000		528		DS	FD	gap	
			529 530		test	routine will be	here (from VRR-a macro)	
			531	*			acto (110m vav a macto)	
			532 533		follo	wed by EXPECTED RESUL	Т	
			333			EALECIED RESUL	.1	

ASMA Ver.	0. 7. 0 zvector- e7	-06-Find (Zv	ector E7 V	/RR-a i	nstructi	on)		14 Feb 2025 21: 40: 22 Page 13
LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
00001118		00000000	0000438F	535 536	ZVE7TST	CSECT DS	, OF	
				538	*****	*****	*****	*********
				539 540	* Ma	cros to		tables ***********
				542 543		to gene	erate individual t	est
				544		Ü	oruce mur vruudi e	
				545 546		MACRO VRR_A	&I NST, &MB, &M5, &CC	
				547 548 549	*			&INST - VRR-a instruction under test &MB - MB field - element size &M5 - M5 field - CS
				550 551	. *			&CC - expected CC
				552	owaa (4)		` ,	mask values for FAILED condition codes
					&XCC(1) &XCC(2)	SETA SETA	7 11	CC != 0 CC != 1
				555	&XCC(3) &XCC(4)	SETA SETA	13	CC != 2 CC != 3
				557	WACC (4)			CC := 3
				558 559	&TNUM		&TNUM &TNUM+1	
				560	W			
				561 562		DS USING	OFD *, R5	base for test data and test routine
				563 564	T&TNUM	DC	A(X&TNUM)	address of test routine
				565	IWINUM	DC	H'&TNUM	test number
				566 567		DC DC	X' 00' HL1' &MB'	MB used
				568		DC	HL1' &M5'	M5 used
				569 570		DC DC	HL1' &CC' HL1' &XCC(&CC+1)'	CC CC failed mask
				571 572		DS	2F	extracted PSW after test (has CC)
				573		DC DC	X' FF'	extracted rsw arter test (has cc) extracted CC, if test failed
				574 575		DC	CL8' &INST'	instruction name
				576		DC	A(RE&TNUM)	address of v1 result
				577 578 579		DC DC DC	A(RE&TNUM+16) A(RE&TNUM+32) A(16)	address of v2 source address of v3 source result length
				581	REA&TNUM V10&TNUM	DS	A(RE&TNUM) FD XL16	result address gap V1 output
				583 584 585	*	DS	FD	gap
				586	X&TNUM	DS I A	OF R1, V1FUDGE	load v21 fudgo
				587 588			v21, 0(R1)	load v21 fudge

.	OD THE		4555	CITTA FE			
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			

				631 *	E7 VRI	R-a tests	***********
				633	PRINT		• ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~ ~
				634 *	1 101 10 1	DATA	
				635 *			
				636 * E75	C VISTR	- Vector Isol	ate String
				637 * 638 *	VRR- a	instruction,	
				639 *	vicit a	MB,	element size
				640 *		M5,	CS
				641 *		CC	expected condition code
				642 * 643 *		followed by	
				644 *		16 byte V1	resul t
				645 *		16 byte V2	source
				646			
						tor Isolate Str	າ nơ
				649 *			
				650			
							CS=1
				652 * case 653 *	U - SII	upre debug	C3=1
				654 *byte			
201110				655		VI STR, 0, 1, 0	
001118 001118		00001118		656+ 657+	DS USING	0FD * D5	base for test data and test routine
001118	00001170	00001110		658+T1	DC	A(X1)	address of test routine
00111C	0001			659 +	DC	H' 1'	test number
)0111E	00			660+		X' 00'	10
00111F 001120	00 01			661+ 662+	DC DC	HL1' 0' HL1' 1'	MB used M5 used
01120				663+	DC	HL1' 0'	CC
001122	07			664 +	DC	HL1' 7'	CC failed mask
001124	00000000 00000000			665+	DS	2F X' FF'	extracted PSW after test (has CC)
00112C 00112D	FF E5C9E2E3 D9404040			666+ 667+	DC DC	CL8' VI STR'	extracted CC, if test failed instruction name
01138	0000119C			668+	DC	A(RE1)	address of v1 result
00113C	000011AC			669+	DC	A(RE1+16)	address of v2 source
001140 001144	000011BC 00000010			670+ 671+	DC DC	A(RE1+32) A(16)	address of v3 source
01144	0000010 0000119C			672+REA1	DC	A(RE1)	result length result address
001150	00000000 00000000			673+	DS	FD	gap
001158	$00000000 \ 00000000$			674+V101	DS	XL16	V1 output
001160 001168				675+	DS	FD	ran
01100				676+*	טע	I D	gap
001170				677+X1	DS	0F	
001170			000010F8	678+	LA	R1, V1FUDGE	load v21 fudge
)01174)0117A	E751 0000 0806 E310 5024 0014		00000000 00000024	679+ 680+	VL LGF	v21, 0(R1) R1, V2ADDR	load v2 source
001178			00000024	681+	VL	v22, 0(R1)	use v21 to test decoder
001186	E756 0010 0C5C			682+	VISTR	V21, V22, 0, 1	test instruction
00118C 001190	B98D 0020 5020 500C		0000000	683+		R2, R0 R2, CCPSW	extract psw
	2020 200		000000C	684 +	ST	KZ LLPNW	to save CC

HL1' 0'

MB used

735 +

0000126F

ASMA Ver. 0.7.0 zvector-e7-06-Find (Zvector E7 VRR-a instruction)

LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
00001270 00001271	01 03			736+ 737+	DC DC	HL1' 1' HL1' 3'	M5 used CC
00001272 00001274 0000127C	0E 00000000 00000000 FF			738+ 739+ 740+	DC DS DC	HL1' 14' 2F X' FF'	CC failed mask extracted PSW after test (has CC) extracted CC, if test failed
0000127D 00001288	E5C9E2E3 D9404040 000012EC			741+ 742+	DC DC	CL8' VISTR' A(RE3)	instruction name address of v1 result
0000128C 00001290 00001294	000012FC 0000130C 00000010			743+ 744+ 745+	DC DC DC	A(RE3+16) A(RE3+32) A(16)	address of v2 source address of v3 source result length
00001298 000012A0 000012A8	000012EC 00000000 00000000 00000000 00000000			746+REA3 747+ 748+V103	DC DS DS	A(RE3) FD XL16	result address gap V1 output
000012B0 000012B0 000012B8	0000000 0000000 00000000 00000000 000000			749 +	DS	FD FD	gap
000012C0 000012C0	4110 8EF8		000010F8	750+* 751+X3 752+	DS LA	OF R1, V1FUDGE	load v21 fudge
000012C4 000012CA	E751 0000 0806 E310 5024 0014		0000000 0000024	753+ 754+	VL LGF	v21, 0(R1) R1, V2ADDR	load v2 source
000012D0 000012D6 000012DC	E761 0000 0806 E756 0010 0C5C B98D 0020		0000000	755+ 756+ 757+	VL VI STR EPSW	v22, 0(R1) V21, V22, 0, 1 R2, R0	use v21 to test decoder test instruction extract psw
000012E0 000012E4 000012EA	5020 500C E750 5040 080E 07FB		0000000C 000012A8	758+ 759+ 760+	ST VST BR	R2, CCPSW V21, V103 R11	to save CC save v1 output return
000012EC 000012EC				761+RE3 762+	DC DROP	0F R5	V1 for this test
000012EC 000012F4 000012FC 00001304	01020304 05060708 090A0B0C 0D0E0F10 01020304 05060708 090A0B0C 0D0E0F10			763 764	DC DC		05060708 090A0B0C 0D0E0F10' v1 05060708 090A0B0C 0D0E0F10' v2

ASIM VEI.	U. 7. U ZVector-e7-	00-1111d (Zv	ector E7	vm-a instructi	OII)		14 Feb 2023 21: 40: 22 Fage
LOC	OBJECT CODE	ADDR1	ADDR2	STM			
				766 *hal fwor	d		
				767		VISTR, 1, 1, 0	
0001310				768 +	DS	OFD	
0001310		00001310		769 +	USING	*, R 5	base for test data and test routine
0001310	00001368			770+T4	DC	A(X4)	address of test routine
0001314	0004			771+	DC	H' 4'	test number
0001316	00			772+	DC	X' 00'	
0001317	01			773+	DC	HL1' 1'	MB used
0001318	01			774+	DC	HL1' 1'	M5 used
001319	00			775+	DC	HL1' 0'	CC
00131A	07			776+	DC	HL1' 7'	CC failed mask
00131C	00000000 00000000			777+	DS	2F	extracted PSW after test (has CC)
001324	FF Escorate Dogogogo			778+	DC DC	X' FF'	extracted CC, if test failed
001325	E5C9E2E3 D9404040			779+ 780+	DC DC	CL8' VISTR'	instruction name address of v1 result
001330 001334	00001394 000013A4			780+ 781+	DC DC	A(RE4) A(RE4+16)	address of vi result address of v2 source
001334	000013A4 000013B4			781+ 782+	DC DC	A(RE4+10) A(RE4+32)	address of v2 source
001336 000133C	000013D4			783+	DC	A(16)	result length
001330	000010			784+REA4	DC	A(RE4)	result address
001348	00000000 00000000			785+	DS	FD	
001340	0000000 0000000			786+V104	DS	XL16	gap V1 output
001358	0000000 00000000			70017101	DO	ALIU	VI oucput
001360	0000000 00000000			787 +	DS	FD	gap
001000				788+*	D.S	12	8 - r
001368				789+X4	DS	0F	
001368	4110 8EF8		000010F8	790+	LA	R1, V1FUDGE	load v21 fudge
000136C	E751 0000 0806		00000000	791+	VL	v21, 0(R1)	
0001372	E310 5024 0014		00000024	792 +	LGF	R1, V2ADDR	load v2 source
0001378	E761 0000 0806		00000000	793+	$\overline{\mathbf{VL}}$	v22, 0(R1)	use v21 to test decoder
000137E	E756 0010 1C5C			794+		V21, V22, 1, 1	test instruction
0001384	B98D 0020			795 +	EPSW	R2, R0	extract psw
0001388	5020 500C		000000C	796 +	ST	R2, CCPSW	to save CC
000138C	E750 5040 080E		00001350	797+	VST	V21, V104	save v1 output
0001392	07FB			798 +	BR	R11	return
0001394				799+RE4	DC	OF	V1 for this test
0001394				800 +	DROP	R 5	
0001394	0000000 00000000			801	DC	XL16' 00000000	00000000 00000000 00000000' V1
000139C	00000000 00000000						
00013A4	00000000 00000000			802	DC	XL16' 00000000	00000000 00000000 00000000' v2
0013AC	0000000 00000000			000			
				803	T/DD A	VI CIDD 4 4 A	
001000				804		VISTR, 1, 1, 0	
00013B8		00001000		805+	DS	OFD	have Completely and took complete
0013B8	00001410	000013B8		806+	USING		base for test data and test routine
00013B8	00001410			807+T5	DC DC	A(X5)	address of test routine
0013BC	0005			808+	DC DC	H' 5' X' 00'	test number
00013BE 00013BF	00 01			809+ 810+	DC DC	HL1' 1'	MB used
)0013BF)0013C0	01			810+ 811+	DC DC	HL1'1'	M5 used
0013C0 00013C1	00			812+	DC DC	HL1' 0'	CC Wb used
00013C1	07			813+	DC DC	HL1'7'	CC failed mask
00013C2	00000000 00000000			814+	DS DS	2F	extracted PSW after test (has CC)
00013C4	FF			815+	DC DC	X' FF'	extracted FSW after test (has cc) extracted CC, if test failed
00013CC	E5C9E2E3 D9404040			816+	DC	CL8' VISTR'	instruction name
00013CB	0000143C			817+	DC DC	A(RE5)	address of v1 result
0013DC	0000143C 0000144C			818+	DC	A(RE5+16)	address of v1 resurce
OUTODO	OUUUITTU			010+	DC	M(MLUTIU)	audi CBB VI VA BUUI CE

R2, CCPSW

to save CC

5020 500C

000014D8

000000C

870 +

	U. 7. U Zvector-e7-	oo iina (2)			1011)		14 Feb 2023 21: 40: 22 Fage
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
				878 *word			
				879	VRR_A	VI STR, 2, 1, 0	
0001508				880 +	DS	OFD	
0001508		00001508		881+	USING	*, R5	base for test data and test routine
0001508	00001560			882+T7	DC	A(X7)	address of test routine
000150C	0007			883+	DC	H' 7'	test number
000150E	00			884+	DC	X' 00'	
000150F	02			885+	DC	HL1' 2'	MB used
001510	01			886+	DC	HL1' 1'	M5 used
001511	00			887+	DC	HL1' 0'	CC
001512	07			888+	DC	HL1' 7'	CC failed mask
001514	00000000 00000000			889+	DS	2F	extracted PSW after test (has CC)
000151C	FF			890+	DC	X' FF'	extracted CC, if test failed
00151D	E5C9E2E3 D9404040			891+	DC	CL8' VISTR'	instruction name
001512	0000158C			892+	DC	A(RE7)	address of v1 result
000152C	0000158C 0000159C			893+	DC	A(RE7+16)	address of v2 source
001520	0000139C 000015AC			894+	DC DC	A(RE7+10) A(RE7+32)	address of v2 source
0001534	000013AC 00000010			895+	DC	A(16)	result length
0001534	0000010 0000158C			896+REA7	DC DC		result address
	00000000 00000000			897+	DS DS	A(RE7) FD	
0001540				898+V107	DS DS	XL16	gap V1 output
0001548	00000000 00000000			898+1107	DЗ	ALIO	vi output
0001550	00000000 00000000			000	DC	T'D	
001558	0000000 00000000			899+	DS	FD	gap
0001500				900+*	D.C.	O.T.	
0001560	4440 0000		00004050	901+X7	DS	OF	1 1 04 0 1
0001560	4110 8EF8		000010F8	902+	LA	R1, V1FUDGE	load v21 fudge
0001564	E751 0000 0806		0000000	903+	VL	v21, 0(R1)	1 1 0
000156A	E310 5024 0014		00000024	904+	LGF	R1, V2ADDR	load v2 source
0001570	E761 0000 0806		0000000	905+	VL	v22, 0(R1)	use v21 to test decoder
0001576	E756 0010 2C5C			906+		V21, V22, 2, 1	test instruction
000157C	B98D 0020			907+		R2, R0	extract psw
0001580	5020 500C		000000C	908+	ST	R2, CCPSW	to save CC
0001584	E750 5040 080E		00001548	909+	VST	V21, V107	save v1 output
000158A	07FB			910+	BR	R11	return
000158C				911+RE7	DC	0F	V1 for this test
000158C				912+	DROP	R5	
000158C	0000000 00000000			913	DC	XL16' 00000000	00000000 00000000 00000000' V1
0001594	0000000 00000000						
000159C	0000000 00000000			914	DC	XL16' 00000000	00000000 00000000 00000000' v2
00015A4	0000000 00000000						
				915			
				916	VRR A	VISTR, 2, 1, 0	
00015B0				917+	DS	OFD	
0015B0		000015B0		918+	USING		base for test data and test routine
0015B0	00001608	00000000		919+T8	DC	A(X8)	address of test routine
00015B4	0008			920+	DC	H' 8'	test number
0015B6	00			921+	DC	X' 00'	
0015B7	02			922+	DC	HL1'2'	MB used
0015B8	01			923+	DC	HL1' 1'	M5 used
0015B9	00			924+	DC	HL1' 0'	CC
0015B3	07			925+	DC	HL1' 7'	CC failed mask
00015BA	00000000 00000000			925+ 926+	DS DS	2F	extracted PSW after test (has CC)
00015BC	FF			927+	DC DC	X' FF'	extracted FSW after test (has cc) extracted CC, if test failed
00015C4	E5C9E2E3 D9404040			927+ 928+	DC	CL8' VISTR'	instruction name
00015C5	00001634			928+ 929+	DC DC		address of v1 result
00015D4				929+ 930+	DC DC	A(RE8)	
JUU I JU4	00001644			33U+	שע	A(RE8+16)	address of v2 source

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LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
000015D8	00001654			931+	DC	A(RE8+32)	address of v3 source	
000015DC	00000010			932+	DC	A(16)	result length	
000015E0	00001634			933+REA8	DC	A(RE8)	result address	
000015E8	0000000 00000000			934+	DS	FĎ		
000015F0	0000000 00000000			935+V108	DS	XL16	gap V1 output	
000015F8	0000000 00000000							
00001600	0000000 00000000			936+	DS	FD	gap	
				937+*				
00001608				938+X8	DS	0F		
00001608	4110 8EF8		000010F8	939+	LA	R1, V1FUDGE	load v21 fudge	
0000160C	E751 0000 0806		00000000	940+	VL	v21, 0(R1)		
00001612	E310 5024 0014		00000024	941+	LGF	R1, V2ADDR	load v2 source	
00001618	E761 0000 0806		0000000	942+	VL	v22, 0(R1)	use v21 to test decoder	
0000161E	E756 0010 2C5C			943+		V21, V22, 2, 1	test instruction	
00001624	B98D 0020		0000000	944+	EPSW	R2, R0	extract psw	
00001628	5020 500C		000000C	945+	ST	R2, CCPSW	to save CC	
0000162C	E750 5040 080E		000015F0	946+	VST	V21, V108	save v1 output	
00001632	07FB			947+	BR	R11	return	
00001634				948+RE8	DC	OF	V1 for this test	
00001634	10202040 00000000			949+	DROP	R5	0000000 0000000 00000000 V1	
00001634	10203040 00000000			950	DC	XL10 01020304	00000000 00000000 000000000' V1	
0000163C 00001644	0000000 00000000			051	DC	VI 16! 01090904	0000000 OFFEFFE FFFFFFFF9	
	10203040 00000000 FFFFFFF FFFFFFF			951	DC	AL10 01020304	0000000 0FFFFFF FFFFFFFF v2	
00001040	FFFFFFF FFFFFFF			952				
					T/DD A	VI CUD O 1 O		
				u53	VKK A	VINIKYIX		
00001658				953 954±		VI STR, 2, 1, 3		
00001658 00001658		00001658		954+	DS	OFD	hase for test data and test routine	
00001658	000016R0	00001658		954+ 955+	DS USI NG	0FD *, R5	base for test data and test routine	
00001658 00001658	000016B0 0009	00001658		954+ 955+ 956+T9	DS USING DC	OFD *, R5 A(X9)	address of test routine	
00001658 00001658 0000165C	0009	00001658		954+ 955+ 956+T9 957+	DS USING DC DC	OFD *, R5 A(X9) H' 9'		
00001658 00001658 0000165C 0000165E	0009 00	00001658		954+ 955+ 956+T9 957+ 958+	DS USING DC DC DC	OFD *, R5 A(X9) H' 9' X' 00'	address of test routine test number	
00001658 00001658 0000165C	0009	00001658		954+ 955+ 956+T9 957+ 958+ 959+	DS USING DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2'	address of test routine test number MB used	
00001658 00001658 0000165C 0000165E 0000165F 00001660	0009 00 02 01	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+	DS USING DC DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1'	address of test routine test number	
00001658 00001658 0000165C 0000165E 0000165F	0009 00 02 01	00001658		954+ 955+ 956+T9 957+ 958+ 959+	DS USING DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2'	address of test routine test number MB used M5 used	
00001658 00001658 0000165C 0000165E 0000166F 00001660 00001661	0009 00 02 01 03	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+	DS USING DC DC DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3'	address of test routine test number MB used M5 used CC CC failed mask	
00001658 00001658 0000165C 0000165E 0000166F 00001661 00001662	0009 00 02 01 03 0E 00000000 00000000 FF	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+	DS USING DC DC DC DC DC DC DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 1' HL1' 3' HL1' 14'	address of test routine test number MB used M5 used CC	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D	0009 00 02 01 03 0E 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001664 0000166C 0000166D 00001678	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167S	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source	
00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source	
00001658 00001658 0000165C 0000165E 00001660 00001661 00001662 00001664 0000166C 0000166D 00001678 0000167C 00001680 00001684	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 00000010	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 966+ 966+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167C 00001680 00001684 00001688	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 00000010 000016DC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 966+ 967+ 968+ 969+ 970+REA9	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 00000010 000016DC 000016DC	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 966+ 967+ 968+ 969+ 970+REA9 971+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000010 000016DC 00000000 00000000 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 966+ 967+ 968+ 969+ 970+REA9	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000010 000016DC 00000000 00000000 00000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap	
00001658 0000165C 0000165E 0000165E 0000166D 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001688 00001690 00001640 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000	00001658		954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001658 0000165C 0000165E 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698 000016A0 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 0000000 0000000 00000000 000000	00001658	000010E9	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 969+ 970+REA9 971+ 972+V109	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001698 000016A0 000016A0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 0000000 0000000 0000000 0000000	00001658	000010F8	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1 FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 00001664 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001690 000016A0 000016B0 000016B0 000016B0	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000016DC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	00000000	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 977+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1 FUDGE v21, O(R1)	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167C 00001680 00001684 00001688 00001690 00001690 000016A0 000016A0 000016B0 000016B0 000016B4 000016B4	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	0000000 0000024	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 977+ 978+	DS USING DC	OFD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166C 0000167C 00001680 00001684 00001688 00001690 00001698 000016A0 000016A0 000016B0 000016B0 000016B4 000016B4 000016BA	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	00000000	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 978+ 979+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder	
00001658 0000165C 0000165E 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166D 0000167C 00001680 00001680 00001688 00001690 00001690 000016A0 000016B0 000016B0 000016B0 000016BA 000016BA 000016CO 000016CO	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	0000000 0000024	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 977+ 978+ 979+ 980+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 3' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1) V21, V22, 2, 1	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder test instruction	
00001658 00001658 0000165C 0000165E 0000165F 00001660 00001661 00001662 0000166C 0000166C 0000167C 00001680 00001684 00001688 00001690 00001698 000016A0 000016A0 000016B0 000016B0 000016B4 000016B4 000016BA	0009 00 02 01 03 0E 00000000 00000000 FF E5C9E2E3 D9404040 000016DC 000016EC 000016FC 0000010 000016DC 0000000 00000000 0000000 00000000 000000	00001658	0000000 0000024	954+ 955+ 956+T9 957+ 958+ 959+ 960+ 961+ 962+ 963+ 964+ 965+ 966+ 967+ 968+ 970+REA9 971+ 972+V109 973+ 974+* 975+X9 976+ 978+ 979+	DS USING DC	0FD *, R5 A(X9) H' 9' X' 00' HL1' 2' HL1' 1' HL1' 14' 2F X' FF' CL8' VI STR' A(RE9) A(RE9+16) A(RE9+32) A(16) A(RE9) FD XL16 FD OF R1, V1FUDGE v21, O(R1) R1, V2ADDR v22, O(R1)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge load v2 source use v21 to test decoder	

1042 +

000017BC

FF

X' FF'

extracted CC, if test failed

ASMA Ver.	0. 7. 0 zvector- e7- 0	6-Find (Zv	ector E7 V	RR-a instructi	on)		14 Feb 2025 21: 40: 22 Page 25	5
LOC	OBJECT CODE	ADDR1	ADDR2	STMI				
000017BD	E5C9E2E3 D9404040			1043+	DC	CL8' VISTR'	instruction name	
000017C8	0000182C			1044+	DC	A(RE11)	address of v1 result	
000017CC	0000183C			1045+	DC	A(RE11+16)	address of v2 source	
000017D0	0000184C			1046+	DC	A(RE11+32)	address of v3 source	
000017D4	0000010			1047+	DC	A(16)	result length	
000017D8 000017E0	0000182C 0000000 00000000			1048+REA11 1049+	DC DS	A(RE11) FD	result address	
000017E0 000017E8	0000000 0000000			1049+ 1050+V1011	DS DS	XL16	gap V1 output	
000017E0	0000000 0000000			1000 11011	DO	ALIO	VI oucpue	
000017F8	00000000 00000000			1051+ 1052+*	DS	FD	gap	
00001800				1053+X11	DS	0F		
00001800	4110 8EF8		000010F8	1054+	LA	R1, V1FUDGE	load v21 fudge	
00001804	E751 0000 0806		00000000	1055+	VL	v21, 0(R1)	1 - 1 - 0	
0000180A 00001810	E310 5024 0014 E761 0000 0806		00000024 00000000	1056+ 1057+	LGF VL	R1, V2ADDR	load v2 source use v21 to test decoder	
00001810	E756 0010 0C5C		0000000	1057+ 1058+		v22, 0(R1) V21, V22, 0, 1	test instruction	
00001810 0000181C	B98D 0020			1059+	EPSW	R2, R0	extract psw	
00001820	5020 500C		000000C	1060+	ST	R2, CCPSW	to save CC	
00001824	E750 5040 080E		000017E8	1061+	VST	V21, V1011	save v1 output	
0000182A	07FB			1062+	BR	R11	return	
0000182C				1063+RE11	DC	0F	V1 for this test	
0000182C	01000004 05000700			1064+	DROP	R5	OFOCOTOR ODOLODOC ODOFOCOL1	
0000182C 00001834	01020304 05060708 090A0B0C 0D0E0F00			1065	DC	XL10 01020304	05060708 090A0B0C 0D0E0F00' v1	
00001834 0000183C	01020304 05060708			1066	DC	XI.16' 01020304	05060708 090A0B0C 0D0E0F00' v2	
				1000	DC	ALIO OIO~OOOI	00000700 000M0D0C 0D0L0T00 V×	
00001844	O9OAOBOC ODOEOFOO							
00001844	090A0B0C 0D0E0F00			1067				
	О9ОАОВОС ОДОЕОГОО			1068		VISTR, 0, 1, 0		
00001850	О9ОАОВОС ОДОЕОГОО	00001070		1068 1069+	DS	OFD		
00001850 00001850		00001850		1068 1069+ 1070+	DS USING	OFD *, R5	base for test data and test routine	
00001850 00001850 00001850	000018A8	00001850		1068 1069+ 1070+ 1071+T12	DS USING DC	0FD *, R5 A(X12)	address of test routine	
00001850 00001850 00001850 00001854	000018A8 000C	00001850		1068 1069+ 1070+ 1071+T12 1072+	DS USING DC DC	OFD *, R5 A(X12) H' 12'		
00001850 00001850 00001850	000018A8 000C	00001850		1068 1069+ 1070+ 1071+T12	DS USING DC DC DC	OFD *, R5 A(X12) H' 12' X' 00'	address of test routine	
00001850 00001850 00001850 00001854 00001856	000018A8 000C 00	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+	DS USING DC DC DC DC DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1'	address of test routine test number MB used M5 used	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001859	000018A8 000C 00 00 01	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+	DS USING DC DC DC DC DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 1'	address of test routine test number M3 used M5 used CC	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001859	000018A8 000C 00 00 01 00 07	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+	DS USING DC DC DC DC DC DC DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 1' HL1' 7'	address of test routine test number MB used M5 used CC CC failed mask	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001859 0000185A	000018A8 000C 00 00 01 00 07 00000000 00000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+	DS USING DC DC DC DC DC DC DC DC DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC)	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001859 0000185C 00001864	000018A8 000C 00 00 01 00 07 00000000 00000000 FF	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+	DS USING DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001859 0000185A 0000185C 00001864	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+	DS USING DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001859 0000185C 00001864	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+	DS USING DC	0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185A 00001864 00001865 00001870 00001874	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+	DS USING DC	OFD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185A 00001864 00001865 00001870 00001878 00001878	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 000018F4 00000010	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+	DS USING DC	0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001878 00001878 0000187C 00001880	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 0000018F4 0000018D4	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12	DS USING DC	0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+32) A(16) A(RE12)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001870 00001870 00001870 00001870 00001880 00001880	000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 0000018F4 00000010 000018D4 0000018D4 000000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+32) A(16) A(RE12) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001874 00001870 00001870 00001870 00001880 00001880	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018D4 0000018D4 0000018D4 00000000 00000000 00000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12	DS USING DC	0FD *, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+32) A(16) A(RE12)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001870 00001870 00001870 00001880 00001880 00001880 00001890 00001898	000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018E4 000018F4 0000010 000018D4 00000000 00000000 00000000 00000000 00000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001874 00001870 00001870 00001870 00001880 00001880	000018A8 000C 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018D4 0000018D4 0000018D4 00000000 00000000 00000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+32) A(16) A(RE12) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 0000185A 0000185C 00001864 00001865 00001870 00001870 00001870 00001870 00001880 00001880 00001880 00001890 00001898	000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018D4 0000010 000018D4 00000000 00000000 00000000 00000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1075+ 1076+ 1077+ 1078+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001858 0000185A 0000185C 00001864 00001865 00001870 00001870 00001878 00001870 00001880 00001880 00001888	000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018D4 0000010 000018D4 00000000 00000000 00000000 00000000	00001850	000010F8	1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012 1088+ 1090+X12 1091+	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001858 0000185C 00001864 00001865 00001870 00001870 00001870 00001870 00001880 00001880 00001880 00001888	000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 000018B4 0000010 000018D4 0000000 00000000 00000000 00000000 00000000	00001850	00000000	1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012 1088+ 1090+X12 1091+ 1092+	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF R1, V1FUDGE v21, O(R1)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge	
00001850 00001850 00001850 00001854 00001856 00001857 00001858 00001858 0000185A 0000185C 00001864 00001865 00001870 00001878 00001878 00001878 00001880 00001888 00001890 00001888	000018A8 000C 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 000018D4 000018F4 0000018D4 0000010 000018D4 00000000 00000000 00000000 00000000	00001850		1068 1069+ 1070+ 1071+T12 1072+ 1073+ 1074+ 1075+ 1076+ 1077+ 1078+ 1079+ 1080+ 1081+ 1082+ 1083+ 1084+ 1085+REA12 1086+ 1087+V1012 1088+ 1090+X12 1091+	DS USING DC	*, R5 A(X12) H' 12' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE12) A(RE12+16) A(RE12+32) A(16) A(RE12) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap	

ASMA ver.	0. 7. 0 zvector- e7- 0	16-FING (ZV	ector E/ V.	kk-a instructi	on)		14 Feb 2025 21: 40: 22 Page 26
LOC	OBJECT CODE	ADDR1	ADDR2	STMI			
000018BE 000018C4	E756 0010 0C5C B98D 0020			1095+ 1096+	EPSW	V21, V22, 0, 1 R2, R0	test instruction extract psw
000018C8 000018CC	5020 500C E750 5040 080E		000000C 00001890	1097+ 1098+	ST VST	R2, CCPSW V21, V1012	to save CC save v1 output
000018CC 000018D2	07FB		00001830	1099+	BR	R11	return
000018D4				1100+RE12	DC	0F	V1 for this test
000018D4 000018D4	01020304 05060708			1101+ 1102	DROP DC	R5	05060708 090A0B0C 0D000000' v1
000018DC	090A0B0C 0D000000			1102	DС	AL10 01020304	USUOU7U8 USUAUBUC UDUUUUUU VI
000018E4	01020304 05060708			1103	DC	XL16' 01020304	05060708 090A0B0C 0D000F10' v2
000018EC	090A0B0C 0D000F10			1104			
				1104	VRR A	VI STR, 0, 1, 0	
000018F8				1106+	DS	OFD	
000018F8	00001050	000018F8		1107+	USING		base for test data and test routine
000018F8 000018FC	00001950 000D			1108+T13 1109+	DC DC	A(X13) H' 13'	address of test routine test number
000018FE	00			1110+	DC	X' 00'	cese number
000018FF	00			1111+	DC	HL1' 0'	MB used
00001900 00001901	01 00			1112+ 1113+	DC DC	HL1' 1' HL1' 0'	M5 used CC
00001901	07			1113+ 1114+	DC DC	IL1 0 IL1' 7'	CC failed mask
00001904	0000000 00000000			1115+	DS	2F	extracted PSW after test (has CC)
0000190C				1116+	DC	X' FF'	extracted CC, if test failed
0000190D 00001918	E5C9E2E3 D9404040 0000197C			1117+ 1118+	DC DC	CL8' VISTR' A(RE13)	instruction name address of v1 result
0000191C	0000198C			1119+	DC	A(RE13+16)	address of v2 source
00001920	0000199C			1120+	DC	A(RE13+32)	address of v3 source
00001924 00001928	00000010 0000197C			1121+ 1122+REA13	DC DC	A(16) A(RE13)	result length result address
00001930	00000000 00000000			1123+	DS	FD	
00001938	00000000 00000000			1124+V1013	DS	XL16	gap V1 output
00001940 00001948	00000000 00000000 0000000 00000000			1125+	DS	FD	gan
00001340	00000000 00000000			1125+ 1126+*	DS	T D	gap
00001950				1127+X13	DS	OF	
00001950 00001954	4110 8EF8 E751 0000 0806		000010F8 00000000	1128+ 1129+	LA VL	R1, V1FUDGE v21, O(R1)	load v21 fudge
0000195A	E310 5024 0014		0000000	1130+	LGF	R1, V2ADDR	load v2 source
00001960	E761 0000 0806		00000000	1131+	VL	v22, 0(R1)	use v21 to test decoder
00001966	E756 0010 0C5C			1132+	VISTR	V21, V22, 0, 1	test instruction
0000196C 00001970	B98D 0020 5020 500C		000000C	1133+ 1134+	EPSW ST	R2, R0 R2, CCPSW	extract psw to save CC
00001974	E750 5040 080E			1135+	VST	V21, V1013	save v1 output
0000197A	07FB			1136+	BR	R11	return
0000197C 0000197C				1137+RE13 1138+	DC DROP	OF R5	V1 for this test
0000197C	01020304 05060708			1139	DC		05060708 090A0B0C 00000000' v1
00001984	090A0B0C 00000000						
0000198C 00001994	01020304 05060708 090A0B0C 000E0F10			1140	DC	XL16' 01020304	05060708 090A0B0C 000E0F10' v2
00001334	UJUAUDUC UUUEUF1U			1141			
				1142		VISTR, 0, 1, 0	
000019A0		00001040		1143+	DS	OFD * DE	has for tost data and tost worther
000019A0 000019A0	000019F8	000019A0		1144+ 1145+T14	USI NG DC	*, R5 A(X14)	base for test data and test routine address of test routine
JUUJIJAU	00001010			11101111	DU	M(MII)	audi CSS VI CCSC I VUCI IIC

ASWA Ver	0. /. 0 zvector-e/-	JO-FINA (ZV	ector E7 v.	KK-a Instructi	OII)		14 Feb 2025 21: 40: 22 Page 2	7
LOC	OBJECT CODE	ADDR1	ADDR2	STMI				
000019A4	000E			1146+	DC	H' 14'	test number	
000019A4	00			1147+	DC	X' 00'	cest number	
000019A7	00			1148+	DC	HL1' 0'	MB used	
000019A7	01			1149+	DC	HL1' 1'	M5 used	
000019A9	00			1145+ 1150+	DC	HL1' 0'	CC	
000019AA	07			1151+	DC	HL1' 7'	CC failed mask	
000019AC	00000000 00000000			1152+	DS	2F	extracted PSW after test (has CC)	
000019R4	FF			1153+	DC	X' FF'	extracted CC, if test failed	
000019B5				1154+	DC	CL8' VISTR'	instruction name	
000019C0				1155+	DC	A(RE14)	address of v1 result	
000019C4	00001A34			1156+	DC	A(RE14+16)	address of v2 source	
000019C8	00001A44			1157+	DC	A(RE14+32)	address of v3 source	
000019CC				1158+	DC	A(16)	result length	
000019D0	00001A24			1159+REA14	DC	A(RE14)	result address	
000019D8	0000000 00000000			1160+	DS	FD	gap	
000019E0				1161+V1014	DS	XL16	gap V1 output	
000019E8	00000000 00000000							
000019F0	0000000 00000000			1162+	DS	FD	gap	
00001000				1163+*	DC	OF		
000019F8	4110 OFFO		000010E0	1164+X14	DS	OF	1 1 01 C 1	
000019F8			000010F8	1165+	LA	R1, V1FUDGE	load v21 fudge	
000019FC 00001A02			00000000	1166+	VL LGF	v21, 0(R1)	lood v9 course	
00001A02	E310 5024 0014 E761 0000 0806		00000024 00000000	1167+ 1168+	VL	R1, V2ADDR v22, O(R1)	load v2 source use v21 to test decoder	
00001A08			0000000	1169+	VL	V22, U(R1) V21, V22, 0, 1	test instruction	
00001A0E	B98D 0020			1170+	FPSW	R2, R0	extract psw	
00001A18	5020 500C		000000C	1171+	ST	R2, CCPSW	to save CC	
00001A1C			000019E0	1172+	VST	V21, V1014	save v1 output	
00001A22	07FB			1173+	BR	R11	return	
00001A24				1174+RE14	DC	0F	V1 for this test	
00001A24				1175+	DROP	R5		
00001A24	01020304 05060708			1176	DC	XL16' 01020304	05060708 090A0B00 00000000' v1	
00001A2C				4.4 77	D.C.	WT 4 01 04 00000 4	07000700 00010700 070707101	
00001A34				1177	DC	XL16' 01020304	05060708 090A0B00 0D0E0F10' v2	
00001A3C	090A0B00 0D0E0F10			1170				
				1178 1179	V/DD A	VI STR, 0, 1, 0		
00001A48				1180+	DS DS	0FD		
00001A48		00001A48		1181+	USING		base for test data and test routine	
00001A18	00001AA0			1182+T15	DC	A(X15)	address of test routine	
00001A4C				1183+	DC	H' 15'	test number	
00001A4E	00			1184+	DC	X' 00'		
00001A4F				1185+	DC	HL1' 0'	MB used	
00001A50				1186+	DC	肚1' 1'	M5 used	
00001A51	00			1187+	DC	HL1' 0'	CC	
00001A52	07			1188+	DC	HL1' 7'	CC failed mask	
00001A54	00000000 00000000			1189+	DS	2F	extracted PSW after test (has CC)	
00001A5C 00001A5D				1190+ 1191+	DC DC	X' FF' CL8' VI STR'	extracted CC, if test failed instruction name	
00001A3D 00001A68	00001ACC			1191+ 1192+	DC DC	A(RE15)	address of v1 result	
00001A68				1192+	DC	A(RE15+16)	address of v1 resurce	
00001A0C				1194+	DC	A(RE15+10) A(RE15+32)	address of v2 source	
00001A74	0000010			1195+	DC	A(16)	result length	
00001A78				1196+REA15	DC	A(RE15)	result address	
00001A80				1197+	DS	FD		
00001A88	0000000 00000000			1198+V1015	DS	XL16	gap V1 output	

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI				
00001A90	0000000 00000000							
00001A98	00000000 00000000			1199+	DS	FD	gap	
00004440				1200+*	D.C.	0.17		
00001AA0	4110 OFFO		000010E0	1201+X15	DS	OF	land wolf Codes	
00001AA0 00001AA4	4110 8EF8 E751 0000 0806		000010F8 00000000	1202+ 1203+	LA VL	R1, V1FUDGE v21, O(R1)	load v21 fudge	
00001AAA	E310 5024 0014		0000000	1203+ 1204+	LGF	R1, V2ADDR	load v2 source	
00001AB0	E761 0000 0806		00000000	1205+	VL	v22, 0(R1)	use v21 to test decoder	
00001AB6	E756 0010 0C5C			1206+		V21, V22, 0, 1	test instruction	
00001ABC	B98D 0020			1207+	EPSW	R2, R0	extract psw	
00001AC0	5020 500C		000000C	1208+	ST	R2, CCPSW	to save CC	
00001AC4	E750 5040 080E		00001A88	1209+	VST	V21, V1015	save v1 output	
00001ACA 00001ACC	07FB			1210+ 1211+RE15	BR DC	R11 OF	return V1 for this test	
00001ACC				1212+	DROP	R5	vi for this test	
00001ACC	01020304 05060708			1213	DC		05060708 090A0000 00000000' v1	
00001AD4	090A0000 00000000			1210	20	11210 01020001		
	01020304 05060708			1214	DC	XL16' 01020304	05060708 090A000C 0D0E0F10' v2	
00001AE4	090A000C 0D0E0F10							
				1215	T/DD A	TIT CITTO O 4 O		
000014E0				1216		VISTR, 0, 1, 0		
00001AF0 00001AF0		00001AF0		1217+ 1218+	DS USING	0FD * D5	base for test data and test routine	
00001AF0	00001B48	UUUUTAFU		1219+T16	DC	A(X16)	address of test routine	
00001AF4	0010			1220+	DC	H' 16'	test number	
00001AF6	00			1221+	DC	X' 00'		
00001AF7	00			1222+	DC	HL1' 0'	MB used	
00001AF8	01			1223+	DC	HL1' 1'	M5 used	
00001AF9	00			1224+	DC	HL1' 0'	CC	
00001AFA				1225+ 1226+	DC DS	HL1' 7' 2F	CC failed mask	
00001AFC 00001B04	00000000 00000000 FF			1220+ 1227+	DC DC	X' FF'	extracted PSW after test (has CC) extracted CC, if test failed	
	E5C9E2E3 D9404040			1228+	DC	CL8' VISTR'	instruction name	
00001B10				1229+	DC	A(RE16)	address of v1 result	
00001B14	00001B84			1230+	DC	A(RE16+16)	address of v2 source	
00001B18	00001B94			1231+	DC	A(RE16+32)	address of v3 source	
00001B1C	00000010			1232+	DC	A(16)	result length	
00001B20	00001B74			1233+REA16	DC	A(RE16)	result address	
00001B28 00001B30	$\begin{array}{cccc} 00000000 & 00000000 \\ 00000000 & 00000000$			1234+ 1235+V1016	DS DS	FD XL16	gap V1 output	
00001B30	0000000 0000000			1233711010	טע	ALIU	vi oucpuc	
00001B40	0000000 0000000			1236+	DS	FD	gap	
				1237+*			0 1	
00001B48				1238+X16	DS	0F		
00001B48	4110 8EF8		000010F8	1239+	LA	R1, V1FUDGE	load v21 fudge	
00001B4C	E751 0000 0806		00000000	1240+ 1241+	VL LCE	v21, 0(R1)	lood v9 source	
00001B52 00001B58	E310 5024 0014 E761 0000 0806		00000024 00000000	1241+ 1242+	LGF VL	R1, V2ADDR v22, O(R1)	load v2 source use v21 to test decoder	
00001B5E	E756 0010 0C5C		0000000	1242+ 1243+		V22, U(R1) V21, V22, 0, 1	test instruction	
00001B6L	B98D 0020			1244+		R2, R0	extract psw	
00001B68	5020 500C		000000C	1245+	ST	R2, CCPSW	to save CC	
00001B6C	E750 5040 080E		00001B30	1246+	VST	V21, V1016	save v1 output	
00001B72	07FB			1247+	BR	R11	return	
00001B74				1248+RE16	DC DBOD	OF	V1 for this test	
00001B74 00001B74	01020304 05060708			1249+ 1250	DROP DC	R5	05060708 09000000 00000000' v1	
UUUUID/4	01020304 03000708			1230	DC	AL10 01020304	03000700 03000000 00000000 V1	

1301 +

00001C54

FF

X' FF'

extracted CC, if test failed

1348+* 1349+X19

1350+

1351+

1352+

1353 +

000010F8

00000000

00000024

00000000

DS

LA

VL

LGF

 $\mathbf{0F}$

R1, V1FUDGE

v21, 0(R1)

R1, V2ADDR

v22, 0(R1)

00001D40

00001D40

00001D44

00001D50

4110 8EF8

00001D4A E310 5024 0014

E751 0000 0806

E761 0000 0806

gap

load v21 fudge

load v2 source

use v21 to test decoder

VRR_A VISTR, 0, 1, 0

A(X21)

base for test data and test routine

address of test routine

OFD

USING *, R5

DS

DC

1400

1401

00001E38

1402+

1403+

1404+T21

00001E38

00001E38

00001E38

00001E90

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI				
00001E3C	0015			1405+	DC	H' 21'	test number	
00001E3E	00			1406+	DC	X' 00'		
00001E3F	00			1407+	DC	HL1' 0'	MB used	
00001E40	01			1408+	DC	HL1' 1'	M5 used	
00001E41	00			1409+	DC	HL1' 0'	CC	
00001E42				1410+	DC	HL1' 7'	CC failed mask	
00001E44	0000000 00000000			1411+	DS	2F	extracted PSW after test (has CC)	
00001E4C	FF			1412+	DC	X' FF'	extracted CC, if test failed	
00001E4D	E5C9E2E3 D9404040			1413+	DC	CL8' VISTR'	instruction name	
00001E58	00001EBC			1414+	DC	A(RE21)	address of v1 result	
00001E5C	00001ECC			1415+	DC	A(RE21+16)	address of v2 source	
00001E60	00001EDC			1416+	DC	A(RE21+32)	address of v3 source	
00001E64	0000010			1417+	DC	A(16)	result length	
00001E68	00001EBC			1418+REA21	DC	A(RE21)	result address	
00001E70	0000000 00000000			1419+	DS	FD	gap V1 output	
00001E78	0000000 00000000			1420+V1021	DS	XL16	V1 output	
00001E80	0000000 00000000							
00001E88	0000000 00000000			1421+	DS	FD	gap	
				1422+*			~ -	
00001E90				1423+X21	DS	0F		
00001E90	4110 8EF8		000010F8	1424+	LA	R1, V1FUDGE	load v21 fudge	
00001E94	E751 0000 0806		00000000	1425+	\mathbf{VL}	v21, 0(R1)		
00001E9A	E310 5024 0014		00000024	1426+	LGF	R1, V2ADDR	load v2 source	
00001EA0	E761 0000 0806		00000000	1427+	VL	v22, 0(R1)	use v21 to test decoder	
00001EA6	E756 0010 0C5C			1428+	VISTR	V21, V22, 0, 1	test instruction	
00001EAC	B98D 0020			1429+	EPSW	R2, R0	extract psw	
00001EB0	5020 500C		000000C	1430+	ST	R2, CCPSW	to save CC	
00001EB4	E750 5040 080E		00001E78	1431+	VST	V21, V1021	save v1 output	
00001EBA	07FB			1432+	BR	R11	return	
00001EBC				1433+RE21	DC	0F	V1 for this test	
00001EBC	04000004 00000000			1434+	DROP	R5		
00001EBC	01020304 00000000			1435	DC	XL16' 01020304	00000000 00000000 00000000' v1	
	00000000 00000000			4.400	D.C.	T/T 4 01 04 00 00 4	00000000 00010000 00000000	
	01020304 00060708			1436	DC	XL16' 01020304	00060708 090A0B0C 0D0E0F10' v2	
00001ED4	O9OAOBOC ODOEOF10			4.40				
				1437	T/DD A	TIT CITID O 1 O		
00001EE0				1438		VISTR, 0, 1, 0		
00001EE0		00001EE0		1439+	DS	OFD	have Contract data and that musting	
00001EE0	00001E00	00001EE0		1440+	USING		base for test data and test routine	
00001EE0	00001F38			1441+T22	DC	A(X22)	address of test routine	
00001EE4	0016			1442+	DC	H' 22'	test number	
00001EE6	00			1443+	DC	X' 00'	VD	
00001EE7	00			1444+	DC	HL1' 0'	MB used	
00001EE8	01			1445+	DC	HL1' 1'	M5 used	
00001EE9	00			1446+	DC DC	IL1'0' III 1'7'	CC failed mask	
00001EEA	07			1447+ 1448+	DC DS	HL1' 7' 2F	CC failed mask	
00001EEC 00001EF4	00000000 00000000 FF			1448+ 1449+	DS DC	X' FF'	extracted PSW after test (has CC) extracted CC, if test failed	
00001EF4 00001EF5	E5C9E2E3 D9404040			1449+ 1450+	DC DC	CL8' VISTR'	instruction name	
00001EF5	00001F64			1450+ 1451+	DC DC	A(RE22)	address of v1 result	
00001F00	00001F04 00001F74			1451+ 1452+	DC	A(RE22+16)	address of v1 result address of v2 source	
00001F04 00001F08	00001F74 00001F84			1452+ 1453+	DC DC	A(RE22+32)	address of v2 source	
00001F08	00001164			1453+ 1454+	DC DC	$\begin{array}{c} A(RE22+32) \\ A(16) \end{array}$	result length	
00001F0C	000016 00001F64			1455+REA22	DC	A(RE22)	result address	
00001F10	00001104			1456+	DS DS	FD		
00001F18	0000000 0000000			1457+V1022	DS DS	XL16	gap V1 output	
OUUII AU				1107 11022	D O	ALIU	vi oucpuc	

v1

R2, CCPSW 00002000 5020 500C 000000C 1504+ ST save v1 output 00002004 E750 5040 080E 00001FC8 1505+ **VST** V21, V1023 0000200A **07FB** 1506+ **R11** BR return 0000200C

0000200C

0000200C

01020000 00000000

1507+RE23 DC 0F V1 for this test **DROP R5** 1508 +1509 DC XL16' 01020000 00000000 00000000 00000000'

1560 +

000020EC

FF

X' FF'

extracted CC, if test failed

VISTR V21, V22, 1, 1

R2, CCPSW

EPSW R2, R0

test instruction

extract psw

to save CC

1688+

1689+

1690+

000000C

E756 0010 1C5C

B98D 0020

5020 500C

0000233E

00002344

DC

DC

DC

H' 30'

X' 00'

HL1' 1'

test number

MB used

1739 +

1740+

1741 +

00002424

00002426

00002427

001E

00

1791+V1031

1792+

1793+*

DS

DS

XL16

gap

FD

0000000 00000000

0000000 00000000

0000000 00000000

00002508

00002510

DC

DC

XL16' 8888888 00000000 00000000 00000000'

XL16' 8888888 00007777 66666666 55555555'

v1

v2

1843

1844

8888888 00000000

0000000 00000000

8888888 00007777

66666666 55555555

000025F4

000025FC

00002604

0000260C

DC

DC

DC

DC

X' FF'

CL8' VISTR'

A(RE34+16)

A(RE34)

1894+

1895 +

1896+

1897 +

000026D4

000026D5

000026E0

000026E4

FF

00002744

00002754

E5C9E2E3 D9404040

extracted CC, if test failed

instruction name

address of v1 result

address of v2 source

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LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
				1920 *word				
				1920 word 1921	VRR A	VI STR, 2, 1, 3		
00002768				1922+	DS DS	0FD		
00002768		00002768		1923+	USING		base for test data and test routine	
00002768	000027C0			1924+T35	DC	A(X35)	address of test routine	
0000276C	0023			1925+	DC	H' 35'	test number	
0000276E 0000276F	00 02			1926+ 1927+	DC DC	X' 00' HL1' 2'	MP ugod	
00002701	01			1928+	DC	HL1' 1'	MB used M5 used	
00002771	03			1929+	DC	HL1' 3'	CC	
00002772	0E			1930+	DC	HL1' 14'	CC failed mask	
00002774	00000000 00000000			1931+	DS	2F	extracted PSW after test (has CC)	
0000277C	FF			1932+	DC	X' FF'	extracted CC, if test failed	
0000277D	E5C9E2E3 D9404040			1933+	DC	CL8' VISTR'	instruction name	
00002788 0000278C	000027EC 000027FC			1934+ 1935+	DC DC	A(RE35) A(RE35+16)	address of v1 result address of v2 source	
00002780	000027FC 0000280C			1936+	DC	A(RE35+10) A(RE35+32)	address of v2 source	
00002794	00000010			1937+	DC	A(16)	result length	
00002798	000027EC			1938+REA35	DC	A(RE35)	result address	
000027A0	00000000 00000000			1939+	DS	FD	gap	
000027A8	0000000 00000000			1940+V1035	DS	XL16	V1 output	
000027B0 000027B8	0000000 00000000 0000000 00000000			1941+	DS	FD	don	
ооостьо	0000000 0000000			1942+*	טע	ΓD	gap	
000027C0				1943+X35	DS	OF		
000027C0	4110 8EF8		000010F8	1944+	LA	R1, V1FUDGE	load v21 fudge	
000027C4	E751 0000 0806		0000000	1945+	VL	v21, 0(R1)		
000027CA	E310 5024 0014		00000024	1946+	LGF	R1, V2ADDR	load v2 source	
000027D0 000027D6	E761 0000 0806 E756 0010 2C5C		00000000	1947+ 1948+	VL	v22, 0(R1) V21, V22, 2, 1	use v21 to test decoder test instruction	
000027DC	B98D 0020			1949+		R2, R0	extract psw	
000027E0	5020 500C		000000C	1950+	ST	R2, CCPSW	to save CC	
000027E4	E750 5040 080E		000027A8	1951+	VST	V21, V1035	save v1 output	
	07FB			1952+	BR	R11	return	
000027EC 000027EC				1953+RE35	DC DROP	OF R5	V1 for this test	
000027EC	AAAAAAA BBBBBBBB			1954+ 1955	DKOP DC		BBBBBBB CCCCCCC DDDDDDDD' v1	
000027EC	CCCCCCC DDDDDDDD			1000	ЪС	ALIO AAAAAAA	BUBBBBB CCCCCCC DUBBBBB VI	
000027FC	AAAAAAA BBBBBBB			1956	DC	XL16' AAAAAAA	BBBBBBB CCCCCCC DDDDDDDD' v2	
00002804	CCCCCCC DDDDDDDD			1057				
				1957	T/DD A	VICTD 9 1 A		
00002810				1958 1959+	VKK_A DS	VI STR, 2, 1, 0 OFD		
00002810		00002810		1939+ 1960+	USING		base for test data and test routine	
00002810	00002868	0000010		1961+T36	DC	A(X36)	address of test routine	
00002814	0024			1962+	DC	H'36'	test number	
00002816	00			1963+	DC	X' 00'	ND 7	
00002817 00002818	02			1964+ 1965+	DC DC	HL1' 2' HL1' 1'	MB used	
00002818	01 00			1965+ 1966+	DC DC	HL1' 1' HL1' 0'	M5 used CC	
00002819 0000281A	07			1967+	DC	HL1' 7'	CC failed mask	
0000281C	0000000 0000000			1968+	DS	2F	extracted PSW after test (has CC)	
00002824	FF			1969+	DC	X' FF'	extracted CC, if test failed	
00002825	E5C9E2E3 D9404040			1970+	DC	CL8' VISTR'	instruction name	
00002830	00002894			1971+	DC DC	A(RE36)	address of v1 result	
00002834	000028A4			1972+	DC	A(RE36+16)	address of v2 source	

EPSW R2, R0

R2, CCPSW

extract psw

to save CC

2023+

2024+

000000C

0000292C

00002930

B98D 0020

5020 500C

TOO	OBJECT CODE	ADDD1	ADDDO	CONT			
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
002934	E750 5040 080E		000028F8	2025+	VST	V21, V1037	save v1 output
00293A	O7FB			2026+	BR	R11	return
00293C				2027+RE37	DC	0F	V1 for this test
00293C				2028+	DROP	R5	
00293C	AAAAAAA BBBBBBB			2029	DC	XL16' AAAAAAA	BBBBBBB 00000000 00000000' v1
002944	00000000 00000000			222	D .C	T/T 4 0 1 4 4 4 4 4 4 4 4 4 4 4 4 4 4 4 4 4	PREPARA COCCOCC PREPARAL
00294C	AAAAAAA BBBBBBBB			2030	DC	XL16' AAAAAAAA	BBBBBBB 00000000 DDDDDDDD' v2
002954	00000000 DDDDDDDD			0001			
				2031	AVDD A	VI CUD O 1 O	
00000				2032		VI STR, 2, 1, 0	
002960		00000000		2033+	DS	OFD * DF	has for test data and test mention
002960	00000000	00002960		2034+	USING		base for test data and test routine
002960	000029B8			2035+T38	DC	A(X38)	address of test routine
002964	0026 00			2036+ 2037+	DC DC	H' 38' X' 00'	test number
)02966)02967	00 02			2037+ 2038+	DC DC	HL1' 2'	MB used
)02968	01			2039+	DC DC	HL1' 2'	M5 used M5 used
02969	00			2039+ 2040+	DC DC	HL1'0'	CC CC
)0296A	00 07			2040+ 2041+	DC DC	HL1'7'	CC CC failed mask
0296C	00000000 00000000			2041+ 2042+	DS	2F	extracted PSW after test (has CC)
002900	FF			2042+	DC DC	X' FF'	extracted CC, if test failed
02975	E5C9E2E3 D9404040			2044+	DC	CL8' VISTR'	instruction name
02980	000029E4			2045+	DC	A(RE38)	address of v1 result
002984	000029E4 000029F4			2046+	DC	A(RE38+16)	address of v2 source
002988	00002314 00002A04			2047+	DC	A(RE38+32)	address of v2 source
00298C	00000010			2048+	DC	A(16)	result length
002990	000029E4			2049+REA38	DC	A(RE38)	result address
002998	00000000 00000000			2050+	DS	FD	gap
0029A0	0000000 00000000			2051+V1038	DS	XL16	V1 output
0029A8	0000000 00000000			2001111000	DO	ALIO	VI oucput
0029B0	0000000 00000000			2052+	DS	FD	gap
оогово	0000000 00000000			2053+*	DO	1.0	Sup
0029B8				2054+X38	DS	0F	
0029B8	4110 8EF8		000010F8	2055+	LA	R1, V1FUDGE	load v21 fudge
0029BC	E751 0000 0806		00000000	2056+	VL	v21, 0(R1)	
0029C2	E310 5024 0014		00000024	2057+	ĹĠF	R1, V2ADDR	load v2 source
0029C8	E761 0000 0806		00000000	2058+	VL	v22, 0(R1)	use v21 to test decoder
0029CE	E756 0010 2C5C			2059+		V21, V22, 2, 1	test instruction
0029D4	B98D 0020			2060+	EPSW	R2, R0	extract psw
0029D8	5020 500C		000000C	2061+	ST	R2, CCPSW	to save CC
0029DC	E750 5040 080E		000029A0	2062+	VST	V21, V1038	save v1 output
0029E2	O7FB			2063+	BR	R11	return
0029E4				2064+RE38	DC	0F	V1 for this test
0029E4				2065+	DROP	R5	
)029E4	AAAAAAA 00000000			2066	DC	XL16' AAAAAAA	00000000 00000000 00000000' v1
)029EC	0000000 00000000				_		
0029F4	AAAAAAA 0000000			2067	DC	XL16' AAAAAAAA	00000000 CCCCCCC DDDDDDDD' v2
029FC	CCCCCCC DDDDDDDD						
				2068			
				2069		VISTR, 2, 1, 0	
002A08				2070+	DS	OFD	
002A08		00002A08		2071+	USING		base for test data and test routine
002A08	00002A60			2072+T39	DC	A(X39)	address of test routine
002A0C	0027			2073+	DC	Н' 39'	test number
002A0E	00			2074+	DC	X' 00'	
002A0F	02			2075+	DC	HL1' 2'	MB used

R1, V2ADDR

v22, 0(R1)

load v2 source

use v21 to test decoder

LGF

2210+

2211+

00000024

00000000

00002C62

00002C68

E310 5024 0014

E761 0000 0806

2262+T44

DC

A(X44)

address of test routine

00002DA8

00002D50

00002E1C

00002E20

00002E24

00002E28

00002E30

00002E38

00002E8C

00002E9C

0000010

00002E7C

0000000 00000000

0000000 00000000

LOC OBJECT CODE ADDR1 ADDR2 **STM** 00002D54 002C 2263+ DC H' 44' test number 00002D56 00 2264 +DC X' 00' 00002D57 00 2265+ DC HL1'0' MB used 00002D58 2266+ DC HL1'1' 01 M5 used 2267+ HL1'0' CC 00002D59 00 DC 2268+ 00002D5A 07 DC HL1'7' CC failed mask extracted PSW after test (has CC) 2269+ 00002D5C 00000000 00000000 DS 2F 00002D64 2270+ DC X' FF' extracted CC, if test failed FF 2271+ 00002D65 E5C9E2E3 D9404040 DC CL8' VISTR' instruction name 00002D70 00002DD4 2272 +DC A(RE44) address of v1 result 00002DE4 2273+ DC 00002D74 A(RE44+16)address of v2 source A(RE44+32) 00002D78 2274 +DC address of v3 source 00002DF4 00002D7C 0000010 2275 +DC A(16) result length 00002DD4 2276+REA44 DC **A(RE44)** 00002D80 result address 00002D88 0000000 00000000 gap V1 output 2277+ DS FD 00002D90 0000000 00000000 2278+V1044 DS **XL16** 00002D98 0000000 00000000 00002DA0 2279+DS FD 0000000 00000000 gap 2280+* DS 0F 00002DA8 2281+X44 00002DA8 4110 8EF8 000010F8 2282+ LA R1, V1FUDGE load v21 fudge 2283+ v21, 0(R1)00002DAC E751 0000 0806 0000000 VL 00002DB2 E310 5024 0014 00000024 2284+ LGF R1. V2ADDR load v2 source 00002DB8 E761 0000 0806 00000000 2285+ VL v22, 0(R1)use v21 to test decoder VISTR V21, V22, 0, 1 2286+ 00002DBE E756 0010 0C5C test instruction 00002DC4 B98D 0020 2287+ EPSW R2, R0 extract psw 2288+ 00002DC8 5020 500C 000000C ST R2, CCPSW to save CC 00002DCC E750 5040 080E 00002D90 2289+ **VST** V21, V1044 save v1 output 2290+ 00002DD2 07FB BR **R11** return 00002DD4 2291+RE44 DC 0F V1 for this test 00002DD4 2292+ **DROP R5** 00002DD4 01020304 05060708 2293 DC XL16' 01020304 05060708 00000000 00000000' v100002DDC 00000000 00000000 01020304 05060708 2294 DC XL16' 01020304 05060708 000A000C 0D0E0F10' 00002DE4 00002DEC **000A000C 0D0E0F10** 2295 2296 VRR_A VISTR, 0, 1, 0 00002DF8 2297+ DS **OFD** 00002DF8 00002DF8 USING *, R5 2298+ base for test data and test routine 00002E50 2299+T45 DC A(X45) 00002DF8 address of test routine 00002DFC 002D 2300+ DC H' 45' test number X' 00' 00002DFE 00 2301+ DC 00002DFF 00 2302+ DC HL1'0' MB used 2303+ DC HL1'1' 00002E00 01 M5 used 00002E01 2304+ DC HL1'0' CC 00 00002E02 2305 +DC HL1'7' CC failed mask 07 2306+ 2F extracted PSW after test (has CC) 00002E04 0000000 00000000 DS 00002E0C 2307+ DC X' FF' extracted CC, if test failed FF 00002E0D E5C9E2E3 D9404040 2308+ DC CL8' VISTR' instruction name 2309+ DC 00002E18 00002E7C A(RE45) address of v1 result

DC

DC

DC

DC

DS

DS

A(RE45+16)

A(RE45+32)

A(16)

FD

XL16

A(RE45)

address of v2 source address of v3 source

result length

gap V1 output

result address

2310+

2311+

2312+

2314+

2313+REA45

2315+V1045

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LOC	OBJECT CODE	ADDR1	ADDR2	STM					
00002E40	0000000 00000000								
00002E48	00000000 00000000			2316+	DS	FD	gap		
				2317+*			8 1		
00002E50				2318+X45	DS	0F			
00002E50	4110 8EF8		000010F8	2319+	LA	R1, V1FUDGE	load v21 fudge		
00002E54	E751 0000 0806		00000000	2320+	VL	v21, 0(R1)			
00002E5A	E310 5024 0014		00000024	2321+	LGF	R1, V2ADDR	load v2 source		
00002E60	E761 0000 0806		0000000	2322+	VL	v22, 0(R1)	use v21 to test decoder		
00002E66	E756 0010 0C5C			2323+		V21, V22, 0, 1	test instruction		
00002E6C	B98D 0020		0000000	2324+		R2, R0	extract psw		
00002E70 00002E74	5020 500C E750 5040 080E		0000000C 00002E38	2325+ 2326+	ST VST	R2, CCPSW	to save CC		
00002E74	07FB		UUUUZESO	2327+	BR	V21, V1045 R11	save v1 output return		
00002E7A	U/FB			2328+RE45	DC	OF	V1 for this test		
00002E7C				2329+	DROP	R5	vi ioi ems test		
00002E7C	01020304 05060708			2330	DC		05060708 09000000 00000000' v1		
00002E84	09000000 00000000			2000	20	11210 01020001	V1		
				2331	DC	XL16' 01020304	05060708 09000B0C 0D0E0F10' v2		
00002E94									
				2332					
				2333		VI STR, 0, 1, 0			
00002EA0				2334+	DS	OFD		_	
00002EA0		00002EA0		2335+	USING		base for test data and test	routi ne	
00002EA0	00002EF8			2336+T46	DC	A(X46)	address of test routine		
00002EA4	002E			2337+	DC	H' 46'	test number		
00002EA6	00			2338+ 2339+	DC	X' 00' HL1' 0'	MP wood		
00002EA7 00002EA8	00 01			2340+	DC DC	HL1' 1'	M3 used M5 used		
00002EA8	00			2341+	DC DC	HL1' 0'	CC Wb used		
00002EAS	07			2342+	DC	HL1' 7'	CC failed mask		
00002EAC	00000000 00000000			2343+	DS	2F	extracted PSW after test (has	s CC)	
00002EB4	FF			2344+	DC	X' FF'	extracted CC, if test failed		
00002EB5	E5C9E2E3 D9404040			2345+	DC	CL8' VISTR'	instruction name		
00002EC0	00002F24			2346+	DC	A(RE46)	address of v1 result		
00002EC4	00002F34			2347+	DC	A(RE46+16)	address of v2 source		
00002EC8	00002F44			2348+	DC	A(RE46+32)	address of v3 source		
00002ECC	00000010			2349+	DC	A(16)	result length		
00002ED0	00002F24			2350+REA46	DC	A(RE46)	result address		
00002ED8	0000000 00000000			2351+	DS	FD VI 10	gap V1 output		
00002EE0	0000000 00000000			2352+V1046	DS	XL16	vi output		
00002EE8 00002EF0	0000000 0000000 0000000 0000000			2353+	DS	FD	gan		
UUUULEFU				2354+*	טע	·υ	gap		
00002EF8				2355+X46	DS	OF			
00002EF8	4110 8EF8		000010F8	2356+	LA	R1, V1FUDGE	load v21 fudge		
00002EFC	E751 0000 0806		00000000		VL	v21, 0(R1)			
00002F02	E310 5024 0014		00000024	2358+	ĹĠF	R1, V2ADDR	load v2 source		
00002F08	E761 0000 0806		00000000	2359+	VL	v22, 0(R1)	use v21 to test decoder		
00002F0E	E756 0010 0C5C			2360+		V21, V22, 0, 1	test instruction		
00002F14	B98D 0020			2361+		R2, RO	extract psw		
00002F18	5020 500C		000000C	2362+	ST	R2, CCPSW	to save CC		
00002F1C	E750 5040 080E		00002EE0	2363+	VST	V21, V1046	save v1 output		
00002F22	07FB			2364+	BR	R11	return		
00002F24				2365+RE46	DC DDOD	OF D5	V1 for this test		
00002F24	01020304 00000000			2366+ 2367	DROP DC	R5	00000000 00000000 00000000' v1		
JUUULF L4	01020304 00000000			2307	DC	ALIU 01020304	00000000 00000000 00000000' v1		

HL1'0'

HL1'7'

X' FF'

2F

CC

CC failed mask

extracted PSW after test (has CC)

extracted CC, if test failed

DC

DC

DS

DC

2415+

2416+

2417+

2418+

00002FF9

00002FFA

00002FFC

00003004

00

07

FF

DIAL ACI.	0. 7. 0 zvector- e7- 0	16-Find (Zv	ector E/ V	KK-a instructi	on)		14 Feb 2025 21: 40: 22 Page 53
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003005	E5C9E2E3 D9404040			2419+	DC	CL8' VISTR'	instruction name
00003010	00003074			2420+	DC	A(RE48)	address of v1 result
$00003014 \\ 00003018$	$00003084 \\ 00003094$			2421+ 2422+	DC DC	A(RE48+16) A(RE48+32)	address of v2 source address of v3 source
00003018 0000301C	00000010			2422+ 2423+	DC DC	A(RE40+32) A(16)	result length
00003010	00003074			2424+REA48	DC	A(RE48)	result address
00003028	00000000 00000000			2425+	DS	FD	
00003030	0000000 00000000			2426+V1048	DS	XL16	gap V1 output
00003038	0000000 00000000						12 5m3 P 44
00003040	0000000 00000000			2427+ 2428+*	DS	FD	gap
00003048				2429+X48	DS	0F	
00003048	4110 8EF8		000010F8	2430+	LA	R1, V1FUDGE	load v21 fudge
0000304C	E751 0000 0806		00000000	2431+	VL	v21, 0(R1)	
00003052	E310 5024 0014		00000024	2432+	LGF	R1, V2ADDR	load v2 source
00003058	E761 0000 0806		0000000	2433+	VL	v22, 0(R1)	use v21 to test decoder
0000305E	E756 0010 0C5C			2434+	VISTR	V21, V22, 0, 1	test instruction
00003064	B98D 0020		0000000	2435+	EPSW	R2, RO	extract psw
00003068 0000306C	5020 500C E750 5040 080E		0000000C	2436+	ST	R2, CCPSW V21, V1048	to save CC
00003072	07FB		00003030	2437+ 2438+	VST BR	R11	save v1 output return
00003072	OTE			2439+RE48	DC DC	OF	V1 for this test
00003074				2440+	DROP	R5	vi ioi chis test
00003074	01020304 00000000			2441	DC		00000000 00000000 00000000' v1
0000307C	0000000 00000000			~			, -
00003084	01020304 00060008			2442	DC	XL16' 01020304	00060008 090A0B0C 0D0E0F10' v2
0000308C	O9OAOBOC ODOEOF10						
				2443			
				2444		VI STR, 0, 1, 0	
00003098		00002000		2444 2445+	DS	OFD	has for took data and took months
00003098 00003098	000020E0	00003098		2444 2445+ 2446+	DS USING	OFD *, R5	base for test data and test routine
00003098 00003098 00003098	000030F0	00003098		2444 2445+ 2446+ 2447+T49	DS USING DC	0FD *, R5 A(X49)	address of test routine
00003098 00003098 00003098 0000309C	0031	00003098		2444 2445+ 2446+ 2447+T49 2448+	DS USING DC DC	OFD *, R5 A(X49) H' 49'	
00003098 00003098 00003098 0000309C 0000309E	0031 00	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+	DS USING DC DC DC	0FD *, R5 A(X49) H' 49' X' 00'	address of test routine test number
00003098 00003098 00003098 0000309C 0000309F	0031 00 00	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+	DS USING DC DC DC DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0'	address of test routine test number MB used
00003098 00003098 00003098 0000309C 0000309E	0031 00	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+	DS USING DC DC DC DC DC DC	OFD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1'	address of test routine test number
00003098 00003098 00003098 0000309C 0000309F 000030A0 000030A1 000030A2	0031 00 00 01 00 07	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+	DS USING DC DC DC DC DC DC DC DC	OFD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 1' HL1' 7'	address of test routine test number MB used M5 used CC CC failed mask
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2	0031 00 00 01 00 07 00000000 00000000	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+	DS USING DC DC DC DC DC DC DC DC DC	OFD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC)
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030A4	0031 00 00 01 00 07 00000000 00000000 FF	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2453+ 2454+ 2455+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030A4 000030AC	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2456+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR'	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030A4 000030AC 000030AD	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result
00003098 00003098 00003098 0000309C 0000309F 000030A0 000030A1 000030A2 000030A4 000030AC 000030AD 000030B8	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000312C	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source
00003098 00003098 00003098 0000309C 0000309F 000030A0 000030A1 000030A2 000030A4 000030AC 000030B8 000030BC 000030CO	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000312C 0000313C	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2456+ 2456+ 2456+ 2457+ 2458+ 2459+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030AC 000030AD 000030B8 000030BC 000030C0 000030C4	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000312C 0000313C 00000010	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+ 2459+ 2460+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030AC 000030AC 000030BC 000030BC 000030C0 000030C4 000030C8	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 00000010 0000311C	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2456+ 2456+ 2457+ 2458+ 2459+ 2460+ 2461+REA49	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00003098 00003098 00003098 0000309E 0000309E 000030A0 000030A1 000030A2 000030A4 000030AC 000030AD 000030B8 000030BC 000030C0 000030C0 000030C8 000030D0	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 00000010 0000311C 00000000	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2453+ 2456+ 2456+ 2456+ 2456+ 2458+ 2459+ 2460+ 2461+REA49 2462+	DS USING DC	*, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030AC 000030AC 000030BC 000030BC 000030C0 000030C4 000030C8	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 00000010 0000311C	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2456+ 2456+ 2457+ 2458+ 2459+ 2460+ 2461+REA49	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030AC 000030AC 000030BS 000030BC 000030C0 000030C4 000030C8 000030D0 000030D0	0031 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 0000010 0000311C 00000010 00000000 00000000	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2456+ 2456+ 2457+ 2458+ 2459+ 2460+ 2461+REA49 2462+ 2463+V1049	DS USING DC	*, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
00003098 00003098 00003098 0000309E 0000309E 000030A0 000030A1 000030A2 000030AC 000030AC 000030BS 000030BC 000030C0 000030C4 000030C8 000030C8 000030D0 000030E0 000030E0	0031 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 0000010 0000311C 00000000 00000000 00000000 00000000 00000000	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+ 2459+ 2460+ 2461+REA49 2462+ 2463+V1049	DS USING DC	*, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD XL16 FD	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address
00003098 00003098 00003098 0000309E 0000309F 000030A0 000030A1 000030A2 000030A4 000030AC 000030B8 000030BC 000030C0 000030C0 000030C8 000030C8 000030D0 000030D0 000030E0 000030E0	0031 00 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 0000010 0000311C 0000000 00000000 0000000 00000000 000000	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+ 2459+ 2460+ 2461+REA49 2462+ 2463+V1049 2464+ 2465+* 2466+X49	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD XL16 FD	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
00003098 00003098 00003098 0000309E 0000309E 000030A0 000030A1 000030A2 000030A2 000030AC 000030AC 000030BC 000030BC 000030C0 000030C0 000030C0 000030C8 000030D0 000030D8 000030E0 000030F0 000030F0	0031 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 0000010 0000311C 0000000 00000000 00000000 00000000 00000000	00003098	000010F8	2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+ 2460+ 2461+REA49 2462+ 2463+V1049 2464+ 2465+* 2466+X49 2467+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD XL16 FD OF R1, V1FUDGE	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output
00003098 00003098 00003098 0000309E 0000309E 000030A0 000030A1 000030A2 000030A2 000030AC 000030AD 000030B8 000030BC 000030C0 000030C0 000030C8 000030D0 000030D8 000030E0 000030F0 000030F0 000030F0 000030F0	0031 00 01 00 07 00000000 000000000 FF E5C9E2E3 D9404040 0000311C 0000312C 0000313C 0000010 0000311C 0000000 00000000 00000000 00000000 00000000	00003098	00000000	2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+ 2460+ 2461+REA49 2462+ 2463+V1049 2464+ 2465+* 2467+ 2468+	DS USING DC	*, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD XL16 FD OF R1, V1FUDGE v21, O(R1)	address of test routine test number MB used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output gap load v21 fudge
00003098 00003098 00003098 0000309E 0000309E 000030A0 000030A1 000030A2 000030A2 000030AC 000030AC 000030BC 000030BC 000030C0 000030C0 000030C0 000030C8 000030D0 000030D8 000030E0 000030F0 000030F0	0031 00 01 00 07 00000000 00000000 FF E5C9E2E3 D9404040 0000311C 0000313C 0000010 0000311C 0000000 00000000 00000000 00000000 00000000	00003098		2444 2445+ 2446+ 2447+T49 2448+ 2449+ 2450+ 2451+ 2452+ 2453+ 2454+ 2455+ 2456+ 2457+ 2458+ 2460+ 2461+REA49 2462+ 2463+V1049 2464+ 2465+* 2466+X49 2467+	DS USING DC	0FD *, R5 A(X49) H' 49' X' 00' HL1' 0' HL1' 1' HL1' 7' 2F X' FF' CL8' VI STR' A(RE49) A(RE49+16) A(RE49+32) A(16) A(RE49) FD XL16 FD OF R1, V1FUDGE	address of test routine test number M3 used M5 used CC CC failed mask extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source result length result address gap V1 output

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003106 0000310C	E756 0010 0C5C B98D 0020			2471+ 2472+	EPSW	V21, V22, 0, 1 R2, R0	test instruction extract psw
00003110 00003114 0000311A	5020 500C E750 5040 080E 07FB		0000000C 000030D8	2473+ 2474+ 2475+	ST VST BR	R2, CCPSW V21, V1049 R11	to save CC save v1 output return
0000311C 0000311C 0000311C	01020304 00000000			2476+RE49 2477+ 2478	DC DROP DC	OF R5 XL16' 01020304	V1 for this test 00000000 00000000 00000000' v1
00003124 0000312C 00003134	00000000 00000000 01020304 00000708			2479	DC		00000708 090A0B0C 0D0E0F10' v2
00003140				2480 2481 2482+	VRR_A DS	VI STR, 0, 1, 0 0FD	
00003140 00003140 00003144	00003198 0032	00003140		2483+ 2484+T50 2485+	USING DC DC		base for test data and test routine address of test routine test number
00003146 00003147 00003148	00 00 01			2486+ 2487+ 2488+	DC DC DC	X' 00' HL1' 0' HL1' 1'	MB used M5 used
00003149 0000314A 0000314C	00 07 00000000 00000000			2489+ 2490+ 2491+	DC DC DS	HL1' 0' HL1' 7' 2F	CC CC failed mask extracted PSW after test (has CC)
00003160	FF E5C9E2E3 D9404040 000031C4			2492+ 2493+ 2494+	DC DC DC	X' FF' CL8' VI STR' A(RE50)	extracted CC, if test failed instruction name address of v1 result
00003164 00003168 0000316C	000031D4 000031E4 00000010			2495+ 2496+ 2497+	DC DC DC	A(RE50+16) A(RE50+32) A(16)	address of v2 source address of v3 source result length
00003170 00003178 00003180	000031C4 00000000 00000000 00000000 00000000			2498+REA50 2499+ 2500+V1050	DC DS DS	A(RE50) FD XL16	result address gap V1 output
00003188 00003190	00000000 00000000 00000000 00000000			2501+ 2502+*	DS	FD	gap
00003198 00003198 0000319C	4110 8EF8 E751 0000 0806		000010F8 00000000	2503+X50 2504+ 2505+	DS LA VL	0F R1, V1FUDGE v21, 0(R1)	load v21 fudge
000031A2 000031A8 000031AE	E310 5024 0014 E761 0000 0806 E756 0010 0C5C		00000024 00000000	2506+ 2507+ 2508+	LGF VL VI STR	R1, V2ADDR v22, O(R1) V21, V22, O, 1	load v2 source use v21 to test decoder test instruction
000031B4 000031B8 000031BC	B98D 0020 5020 500C E750 5040 080E		0000000C 00003180	2509+ 2510+ 2511+	ST VST	R2, R0 R2, CCPSW V21, V1050	extract psw to save CC save v1 output
000031C2 000031C4 000031C4	07FB			2512+ 2513+RE50 2514+	BR DC DROP	R11 OF R5	return V1 for this test
000031C4 000031CC 000031D4	01000000 00000000 00000000 00000000 01000304 00060708			2515 2516	DC DC		00000000 00000000 00000000' v1 00060708 090A0B0C 0D0E0F10' v2
000031DC	090A0B0C 0D0E0F10			2517 2518		VISTR, 0, 1, 0	
000031E8 000031E8 000031E8	00003240	000031E8		2519+ 2520+ 2521+T51	DS USING DC	OFD *, R5 A(X51)	base for test data and test routine address of test routine

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI					
000031EC	0033			2522+	DC	Н' 51'	test number		
000031EE	00			2523+	DC	X' 00'			
000031EF	00			2524+	DC	HL1' 0'	MB used		
000031F0	01			2525+	DC	HL1' 1'	M5 used		
000031F1	00			2526+	DC	HL1' 0'	CC		
000031F2	07			2527+	DC	HL1' 7'	CC failed mask		
000031F4	00000000 00000000			2528+	DS	2F	extracted PSW after test (has CC	()	
000031FC	FF			2529+	DC	X' FF'	extracted CC, if test failed		
000031FD	E5C9E2E3 D9404040			2530+	DC	CL8' VISTR'	instruction name		
00003208	0000326C			2531+	DC	A(RE51)	address of v1 result		
0000320C	0000327C			2532+	DC	A(RE51+16)	address of v2 source		
00003210 00003214	0000328C 00000010			2533+ 2534+	DC DC	A(RE51+32)	address of v3 source		
00003214	0000010 0000326C			2535+REA51	DC DC	A(16) A(RE51)	result length result address		
00003218	00003200			2536+	DS	FD			
00003220	0000000 0000000			2537+V1051	DS DS	XL16	gap V1 output		
00003228	0000000 0000000			2337 T V 1 U 3 1	טט	ALIU	vi oucpuc		
00003230	0000000 0000000			2538+	DS	FD	dan		
00003230	0000000 0000000			2539+*	טע	ľν	gap		
00003240				2540+X51	DS	0F			
00003240	4110 8EF8		000010F8	2541+	LA	R1, V1FUDGE	load v21 fudge		
00003244	E751 0000 0806		00000000	2542+	VL	v21, 0(R1)	Tout val Tuuge		
0000324A	E310 5024 0014		00000024	2543+		R1, V2ADDR	load v2 source		
00003250	E761 0000 0806		00000000	2544+	VL	v22, 0(R1)	use v21 to test decoder		
00003256	E756 0010 0C5C			2545+		V21, V22, 0, 1	test instruction		
0000325C	B98D 0020			2546+	EPSW	R2, R0	extract psw		
00003260	5020 500C		000000C	2547+	ST	R2, CCPSW	to save CC		
00003264	E750 5040 080E		00003228	2548+	VST	V21, V1051	save v1 output		
0000326A	07FB			2549+	BR	R11	return		
0000326C				2550+RE51	DC	0F	V1 for this test		
0000326C				2551+	DROP	R 5			
0000326C	01000000 00000000			2552	DC	XL16' 01000000	00000000 00000000 00000000' v1		
00003274	00000000 00000000			0770	D.C.	WT 401 04000000	07000700 00010700 070707101		
	01000300 05060708			2553	DC	XL16, 01000300	05060708 090A0B0C 0D0E0F10' v2		
00003284	O9OAOBOC ODOEOF10			0554					
				2554	VDD A	VICTD O 1 O			
00002200				2555 2556+		VI STR, 0, 1, 0			
00003290 00003290		00003290		2557+	DS USI NG	OFD * P 5	base for test data and test rout	i ne	
00003290	000032E8	00003230		2558+T52	DC	A(X52)	address of test routine	.i iie	
00003294	0034			2559+	DC	H' 52'	test number		
00003294	00			2560+	DC	X' 00'	CCSC Humbel		
00003297	00			2561+	DC	HL1'0'	M3 used		
00003298	01			2562+	DC	HL1' 1'	M5 used		
00003299	00			2563+	DC	HL1' 0'	CC		
0000329A	07			2564+	DC	HL1' 7'	CC failed mask		
0000329C	0000000 00000000			2565+	DS	2F	extracted PSW after test (has CC	:)	
000032A4	FF			2566+	DC	X' FF'	extracted CC, if test failed		
000032A5	E5C9E2E3 D9404040			2567+	DC	CL8' VISTR'	instruction name		
000032B0	00003314			2568+	DC	A(RE52)	address of v1 result		
000032B4	00003324			2569+	DC	A(RE52+16)	address of v2 source		
000032B8	00003334			2570+	DC	A(RE52+32)	address of v3 source		
000032BC	00000010			2571+	DC	A(16)	result length		
000032C0	00003314			2572+REA52	DC	A(RE52)	result address		
000032C8	00000000 00000000			2573+	DS	FD	gap V1 output		
000032D0	00000000 00000000			2574+V1052	DS	XL16	vi output		

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LOC	OBJECT CODE	ADDR1	ADDR2	STMI						
000032D8	0000000 00000000									
000032E0	00000000 00000000			2575+	DS	FD	gap			
000000000				2576+*	D.C.	OF.				
000032E8 000032E8	4110 8EF8		000010F8	2577+X52 2578+	DS LA	OF R1, V1FUDGE	lood v21 fudgo			
	E751 0000 0806		000010F8	2579+	VL	v21, 0(R1)	load v21 fudge			
000032F2	E310 5024 0014		00000000	2580+	LGF	R1, V2ADDR	load v2 source			
000032F8	E761 0000 0806		00000000	2581+	VL	v22, 0(R1)	use v21 to test decoder			
000032FE	E756 0010 0C5C			2582+		V21, V22, 0, 1	test instruction			
00003304	B98D 0020		0000000	2583+	EPSW	R2, R0	extract psw			
00003308 0000330C	5020 500C E750 5040 080E		000000C 000032D0	2584+ 2585+	ST VST	R2, CCPSW V21, V1052	to save CC			
00003300	07FB		00003200	2586+	BR	R11	save v1 output return			
00003314	0/12			2587+RE52	DC	0F	V1 for this test			
00003314				2588+	DROP	R5				
00003314	01000000 00000000			2589	DC	XL16' 01000000	0000000 00000000 00000000'	v1		
0000331C	0000000 00000000			2500	DC.	VI 16! 0100004	OFOCOTOR COOLOROR ODOFOCIOL	0		
00003324 0000332C	01000004 05060708 090A0B0C 0D0E0F10			2590	DC	AL10 01000004	05060708 090A0B0C 0D0E0F10'	v2		
00003320	OSONODOC ODOLOTTO			2591						
				2592	VRR_A	VISTR, 0, 1, 0				
00003338				2593+	DS	OFD		_		
00003338	00000000	00003338		2594+	USING		base for test data and te	st routi	i ne	
00003338 0000333C	00003390 0035			2595+T53 2596+	DC DC	A(X53) H' 53'	address of test routine test number			
0000333E	0033			2597+	DC DC	X' 00'	cest number			
0000333F	00			2598+	DC	HL1'0'	MB used			
00003340	01			2599 +	DC	HL1' 1'	M5 used			
00003341	00			2600+	DC	HL1' 0'	CC			
00003342 00003344				2601+ 2602+	DC	HL1' 7' 2F	CC failed mask	(has CC)		
00003344 0000334C	00000000 00000000 FF			2602+ 2603+	DS DC	X' FF'	extracted PSW after test extracted CC, if test fail		,	
	E5C9E2E3 D9404040			2604+	DC	CL8' VISTR'	instruction name	ı cu		
00003358				2605 +	DC	A(RE53)	address of v1 result			
0000335C	000033CC			2606+	DC	A(RE53+16)	address of v2 source			
00003360	000033DC			2607+	DC	A(RE53+32)	address of v3 source			
00003364 00003368	00000010 000033BC			2608+ 2609+REA53	DC DC	A(16) A(RE53)	result length result address			
00003370	00000000 00000000			2610+	DS	FD				
00003378	0000000 00000000			2611+V1053	DS	XL16	gap V1 output			
00003380	00000000 00000000			2012	n.c					
00003388	00000000 00000000			2612+	DS	FD	gap			
00003390				2613+* 2614+X53	DS	OF				
00003390	4110 8EF8		000010F8	2615+	LA	R1, V1FUDGE	load v21 fudge			
00003394	E751 0000 0806		00000000	2616+	VL	v21, 0(R1)	Tour the things			
0000339A	E310 5024 0014		0000024	2617+	LGF	R1, V2ADDR	load v2 source			
000033A0	E761 0000 0806		00000000	2618+	VL	v22, 0(R1)	use v21 to test decoder			
000033A6 000033AC	E756 0010 0C5C B98D 0020			2619+ 2620+		V21, V22, 0, 1 R2, R0	test instruction			
000033AC	5020 500C		000000C	2621+	ST	R2, RU R2, CCPSW	extract psw to save CC			
000033B0 000033B4	E750 5040 080E		00003378	2622+	VST	V21, V1053	save v1 output			
000033BA	07FB			2623+	BR	R11	return			
000033BC				2624+RE53	DC	0F	V1 for this test			
000033BC	00000000 0000000			2625+	DROP	R5	0000000 0000000 0000000	1		
000033BC	00000000 00000000			2626	DC	VT10 00000000	0000000 00000000 00000000'	v1		

T 0 0	0. 7. 0 zv 0BJECT			ADDR2	STMT	ucci onj	17	1 Feb 2025	~1. 1 U. &&	ı age	57
00033C4	00000000 00000304	00000000	.1221/1	.122.12	2627	DC	XL16' 00000304 05060708 090A0B0C	ODOEOE10!	9		
0033D4	090A0B0C	05060708 0D0E0F10			2628	DC	AL16 00000304 05060708 090A0B0C	ODUEUF 10	VZ		
					2020						

	U. /. U zvector-e/-	`			OII)		14 Feb 2025 21: 40: 22 Page 5
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				2630 *hal fwor			
00000000				2631		VISTR, 1, 1, 0	
000033E0 000033E0		000033E0		2632+ 2633+	DS USING	0FD * P5	base for test data and test routine
000033E0 000033E0	00003438	00003310		2634+T54	DC	A(X54)	address of test routine
000033E4	0036			2635+	DC	H' 54'	test number
000033E6	00			2636+	DC	X' 00'	
000033E7	01			2637+	DC	HL1' 1'	MB used
000033E8	01 00			2638+ 2639+	DC	HL1' 1'	M5 used CC
000033E9 000033EA	00 07			2640+	DC DC	HL1' 0' HL1' 7'	CC failed mask
000033EC	00000000 00000000			2641+	DS	2F	extracted PSW after test (has CC)
000033F4	FF			2642+	DC	X' FF'	extracted CC, if test failed
000033F5	E5C9E2E3 D9404040			2643+	DC	CL8' VISTR'	instruction name
00003400	00003464			2644+	DC	A(RE54)	address of v1 result
00003404 00003408	00003474 00003484			2645+ 2646+	DC DC	A(RE54+16) A(RE54+32)	address of v2 source address of v3 source
00003408 0000340C	0000010			2647+	DC	A(16)	result length
00003410	00003464			2648+REA54	DC	A(RE54)	result address
00003418	00000000 00000000			2649+	DS	FD	gap V1 output
00003420	00000000 00000000			2650+V1054	DS	XL16	V1 output
00003428 00003430	00000000 00000000 0000000 00000000			2651+	DS	FD	gan
00003430	0000000 0000000			2652+*	D O	T D	gap
00003438				2653+X54	DS	0F	
00003438	4110 8EF8		000010F8	2654+	LA	R1, V1FUDGE	load v21 fudge
0000343C	E751 0000 0806		00000000	2655+	VL LGF	v21, 0(R1)	load v2 source
00003442 00003448	E310 5024 0014 E761 0000 0806		00000024 00000000	2656+ 2657+	VL	R1, V2ADDR v22, O(R1)	use v21 to test decoder
0000344E	E756 0010 1C5C		0000000	2658+		V21, V22, 1, 1	test instruction
00003454	B98D 0020			2659+	EPSW	R2, R0	extract psw
00003458	5020 500C		000000C	2660+	ST	R2, CCPSW	to save CC
0000345C 00003462	E750 5040 080E 07FB		00003420	2661+ 2662+	VST BR	V21, V1054 R11	save v1 output return
00003462	OTE			2663+RE54	DC DC	OF	V1 for this test
00003464				2664+	DROP	R5	VI TOI CHIS COSC
00003464	88888888 77777777			2665	DC	XL16' 8888888	7777777 00000000 00000000' v1
0000346C	0000000 0000000			0000	D.C.	VI 101 00000000	
00003474 0000347C	8888888 7777777 00006666 55550000			2666	DC	XL16, 8888888	7777777 00006666 55550000' v2
00003470	0000000 JJJJ0000			2667			
				2668	VRR_A	VISTR, 1, 1, 0	
00003488		00000105		2669+	DS	OFD	
00003488	000024E0	00003488		2670+ 2671+T55	USING		base for test data and test routine address of test routine
00003488 0000348C	000034E0 0037			2671+155 2672+	DC DC	A(X55) H' 55'	test number
0000348E	0037			2673+	DC DC	X' 00'	COOC MAINSON
0000348F	01			2674+	DC	HL1' 1'	MB used
00003490	01			2675+	DC	HL1' 1'	M5 used
00003491 00003492	00 07			2676+ 2677+	DC DC	HL1' 0' HL1' 7'	CC CC failed mask
00003492	00000000 00000000			2678+	DS DS	2F	extracted PSW after test (has CC)
0000349C	FF			2679+	DC	X' FF'	extracted CC, if test failed
0000349D	E5C9E2E3 D9404040			2680+	DC	CL8' VISTR'	instruction name
000034A8	0000350C			2681+	DC	A(RE55)	address of v1 result
000034AC	0000351C			2682+	DC	A(RE55+16)	address of v2 source

LOC

000034B0

000034B4

000034B8

000034C0

000034C8

000034D0

000034D8

000034E0

000034E0

000034E4

000034EA

000034F0

000034F6

000034FC

00003500

00003504

0000350A

0000350C

0000350C

0000350C

00003514 0000351C

00003524

00003530

00003530

00003530

00003534

00003536

00003544

00003545

00003550

00003554

00003558

0000355C

00003560

00003568

00003570

00003578

0000359E

000035A4

000035A8

OBJECT CODE

0000000 00000000

0000000 00000000

0000000 00000000

0000000 00000000

0000352C

0000010

0000350C

4110 8EF8

B98D 0020

5020 500C

07FB

E751 0000 0806

E310 5024 0014

E761 0000 0806

E756 0010 1C5C

E750 5040 080E

8888888 77777777

0000000 00000000

8888888 77777777

00006666 00005555

E5C9E2E3 D9404040

0000000 00000000

0000000 00000000

E756 0010 1C5C

B98D 0020

5020 500C

00003537 01 00003538 01 00003539 00 0000353A 07 0000353C 0000000 00000000

00003588

0038

00

FF

000035B4 2718+ 2719+ 000035C4 000035D4 2720+ 00000010 2721+ 000035B4 2722+REA56 0000000 00000000 2723+

00003530

ASMA Ver. 0.7.0 zvector-e7-06-Find (Zvector E7 VRR-a instruction)

ADDR1

ADDR2

000010F8

0000000

00000024

0000000

000000C

000034C8

STM

2683+

2684+

2686+

2688+

2691+

2692+

2693+

2694+

2695+

2696+

2697+

2698+

2699+

2701 +

2702

2703

2704 2705

2706+

2707+

2709+

2710+

2711+

2712+

2713+

2714+

2715+

2716+

2717+

2725+

2726+*

2724+V1056

2708+T56

2700+RE55

2689+*

2690+X55

2685+REA55

2687+V1055

DC

DC

DC

DS

DS

DS

DS

LA

VL

LGF

VL

DC

DC

DC

DC

DS

DC

DC

DC

DC

DC

DC

DC

DS

DS

DS

DS LA

VL

LGF

VL

00003580 0000000 00000000 00003588 00003588 4110 8EF8 0000358C E751 0000 0806 00003592 E310 5024 0014 E761 0000 0806 00003598

2727+X56 000010F8 2728+ 2729+ 00000000 00000024 2730+ 2731+ 00000000 2732+ 2733+ 000000C 2734+

R2, CCPSW ST V21, V1055 **VST** BR R11 DC 0F **R5 DROP** DC DC

A(RE55+32)

R1, V1FUDGE

v21, 0(R1)

R1, V2ADDR

v22, 0(R1)

VISTR V21, V22, 1, 1

EPSW R2, R0

A(16)

FD

FD

0F

XL16

A(RE55)

VRR_A VISTR, 1, 1, 0 DS **OFD** USING *, R5 A(X56) DC DC H' 56' X' 00' DC

HL1'1' HL1' 1' HL1'0' HL1'7' 2F X' FF'

CL8' VISTR'

A(RE56+16)

A(RE56+32)

R1, V1FUDGE

v21, 0(R1)R1, V2ADDR

v22, 0(R1)

R2, CCPSW

VISTR V21, V22, 1, 1

EPSW R2, R0

A(RE56)

A(16)

FD

FD

0F

XL16

A(RE56)

instruction name address of v1 result address of v2 source address of v3 source result length result address

> gap V1 output gap

CC

gap

load v2 source use v21 to test decoder

load v21 fudge

test instruction extract psw to save CC

extracted PSW after test (has CC)

extracted CC, if test failed

DC

HL1' 1'

MB used

2785+

00003687

2837+*

OBJECT CODE

E751 0000 0806

E310 5024 0014

E761 0000 0806

E756 0010 1C5C

E750 5040 080E

88880000 00000000

0000000 00000000

E5C9E2E3 D9404040

0000000 00000000

0000000 00000000

0000000 00000000

0000000 00000000

4110 8EF8

B98D 0020

5020 500C

00003828

00003854

00003864

00003874

00000010

00003854

4110 8EF8

B98D 0020

5020 500C

E751 0000 0806

E310 5024 0014

E761 0000 0806

E756 0010 1C5C

E750 5040 080E

003C

00

01

01

00

07

FF

07FB

ASMA Ver. 0.7.0 zvector-e7-06-Find (Zvector E7 VRR-a instruction)

ADDR1

000037D0

ADDR2

000010F8

00000000

00000024

00000000

000000C

00003768

STM

2839+

2840+

2841+

2842+

2843+

2844+

2845+

2846+

2847+

2849 +

2850

2848+RE59

2838+X59

2860+

2861+

2862+

2863+

2864+

2865+

2866+

2867+

2868+

2869+

2871+

2873+

2877+

2878+

2879+

2880+

2881+

2882+

2883+

2884+

2886+

2887

2888

2885+RE60

000010F8

00000000

00000024

00000000

000000C

00003810

2870+REA60

2872+V1060

USING *, R5 DC A(X60)DC H' 60' DC X' 00' **HL1'1'** DC DC HL1' 1' DC

DS

LA

VL

LGF

VL

ST

VST

BR

DC

DC

DC

DS

DC

DS

DC

DC

DC

DC

DC

DC

DC

DS

DS

DS

VL

LGF

VL

ST

VST

BR

DC

DC

DC

DROP

DROP

R1, V1FUDGE

v21, 0(R1)

R1, V2ADDR

v22, 0(R1)

R2, CCPSW

V21, V1059

VISTR V21, V22, 1, 1

R11

0F

R5

VRR_A VISTR, 1, 1, 0

OFD

2F

CL8' VISTR'

A(RE60+16)

A(RE60+32)

A(RE60)

A(16)

FD

FD

XL16

A(RE60)

EPSW R2, R0

HL1' 0' HL1' 7' X' FF'

extracted PSW after test (has CC) extracted CC, if test failed instruction name address of v1 result address of v2 source address of v3 source

result length result address gap V1 output

test number

MB used

M5 used

CC failed mask

gap

CC

2874+* 2875+X60 0F DS R1, V1FUDGE 2876+ LA

v21, 0(R1)R1, V2ADDR v22, 0(R1)

R2, CCPSW

V21, V1060

VISTR V21, V22, 1, 1

R11

0F

R5

EPSW R2, R0

load v2 source use v21 to test decoder

load v21 fudge

test instruction extract psw

to save CC save v1 output return

V1 for this test

XL16' 00000000 00000000 00000000 00000000' v1

XL16' 00000000 77777777 66666666 55555555' v2

00003852	07FB	
00003854		
00003854		
00003854	00000000	00000000
0000385C	00000000	00000000
00003864	00000000	7777777
0000386C	6666666	5555555

L_OC

00003780

00003780

00003784

0000378A

00003790

00003796

0000379C

000037A0

000037A4 000037AA

000037AC

000037AC

000037AC

000037D0

000037D0

000037D4

000037D6

000037D8

000037D9

000037DA

000037DC

000037E4

000037E5

000037F0

000037F4

000037F8

000037FC

00003800

00003808

00003810

00003818

00003820

00003828

00003828

0000382C

00003832

00003838

0000383E

00003844

00003848

0000384C

000037D7

		`					8
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				0000 # 1			
				2890 *word	T/DD A	VICTO O 1 O	
00002070				2891		VISTR, 2, 1, 0	
00003878 00003878		00003878		2892+ 2893+	DS USING	OFD * D5	hase for test data and test routing
00003878	000038D0	00003676		2894+T61	DC DC		base for test data and test routine address of test routine
00003878 0000387C	003D			2895+	DC	A(X61) H' 61'	test number
0000387E	0030			2896+	DC DC	X' 00'	test number
0000387E	02			2897+	DC	HL1'2'	MB used
00003871	01			2898+	DC	HL1' 1'	M5 used
00003881	00			2899+	DC DC	HL1' 0'	CC
00003882	07			2900+	DC DC	HL1' 7'	CC failed mask
00003884	0000000 00000000			2901+	DS	2F	extracted PSW after test (has CC)
0000388C	FF			2902+	DC	X' FF'	extracted CC, if test failed
0000388D	E5C9E2E3 D9404040			2903+	DC	CL8' VI STR'	instruction name
00003898	000038FC			2904+	DC	A(RE61)	address of v1 result
0000389C	0000390C			2905+	DC	A(RE61+16)	address of v2 source
000038A0	0000391C			2906+	DC	A(RE61+32)	address of v3 source
000038A4	0000010			2907+	DC	A(16)	result length
000038A8	000038FC			2908+REA61	DC	A(RE61)	result address
000038B0	0000000 00000000			2909+	DS	FD	gap
000038B8	00000000 00000000			2910+V1061	DS	XL16	V1 output
000038C0	0000000 00000000						
000038C8	0000000 00000000			2911+	DS	FD	gap
00000000				2912+*	DC	ΩE	
000038D0 000038D0	4110 8EF8		000010F8	2913+X61 2914+	DS LA	OF R1, V1FUDGE	load v91 fudgo
000038D4	E751 0000 0806		00001018	2915+	VL	v21, 0(R1)	load v21 fudge
000038DA	E310 5024 0014		00000000	2916+	LGF	R1, V2ADDR	load v2 source
000038E0	E761 0000 0806		00000024	2917+	VL	v22, 0(R1)	use v21 to test decoder
000038E6	E756 0010 2C5C		0000000	2918+	VISTR	V21, V22, 2, 1	test instruction
000038EC	B98D 0020			2919+	EPSW	R2, R0	extract psw
000038F0	5020 500C		000000C	2920+	ST	R2, CCPSW	to save CC
000038F4	E750 5040 080E		000038B8	2921+	VST	V21, V1061	save v1 output
000038FA	07FB			2922+	BR	R11	return
000038FC				2923+RE61	DC	0F	V1 for this test
000038FC				2924+		R5	0000000 0000000 0000000
000038FC	AAAAAAA 00000000			2925	DC	XL16' AAAAAAAA	00000000 00000000 00000000' v1
00003904 0000390C	0000000 0000000 AAAAAAA 0000000			2926	DC	VI 1C! AAAAAAAA	00000000 CCCCCCC 00000000' v2
00003900	CCCCCCC 00000000			2920	DC	ALIU AAAAAAA	0000000 CCCCCCC 00000000 V2
00000014				2927			
				2928	VRR A	A VISTR, 2, 1, 0	
00003920				2929+	DS DS	OFD	
00003920		00003920		2930+	USING		base for test data and test routine
00003920	00003978			2931+T62	DC	A(X62)	address of test routine
00003924	003E			2932+	DC	H' 62'	test number
00003926	00			2933+	DC	X' 00'	
00003927	02			2934+	DC	HL1' 2'	MB used
00003928	01			2935+	DC	HL1' 1'	M5 used
00003929	00			2936+	DC	HL1' 0'	CC Soiled mak
0000392A	07			2937+	DC DC	HL1' 7' 2F	CC failed mask
0000392C 00003934	00000000 00000000 FF			2938+ 2939+	DS DC	Zr X' FF'	extracted PSW after test (has CC) extracted CC, if test failed
00003934	E5C9E2E3 D9404040			2940+	DC DC	CL8' VI STR'	instruction name
00003933	000039A4			2941+	DC DC	A(RE62)	address of v1 result
00003944	000039B4			2942+	DC	A(RE62+16)	address of v2 source
						()	

EPSW R2, R0

R2, CCPSW

extract psw

to save CC

2993+

2994+

000000C

00003A3C

00003A40

B98D 0020

5020 500C

ASMA ver.	0. 7. 0 zvector- e7- 0	6-Fina (Zv	ector E7 V	KK-a instructi	on)		14 Feb 2025	21: 40: 22 P	age	65
LOC	OBJECT CODE	ADDR1	ADDR2	STMI						
00003A44 00003A4A	E750 5040 080E 07FB		00003A08	2995+ 2996+	VST BR	V21, V1063 R11	save v1 output return			
00003A4C 00003A4C 00003A4C	00000000 00000000			2997+RE63 2998+ 2999	DC DROP DC	OF R5 XL16' 00000000	V1 for this test 00000000 00000000 00000000'	v1		
00003A54 00003A5C 00003A64	0000000 00000000 0000000 00000000 CCCCCCC DDDDDDDD			3000	DC		00000000 CCCCCCC DDDDDDDD'	v2		
00003A70				3001 3002 3003+	VRR_A DS	VI STR, 2, 1, 0 0FD				
00003A70 00003A70 00003A74	00003AC8 0040	00003A70		3004+ 3005+T64 3006+	USING DC DC		base for test data and taddress of test routine test number		ie	
00003A76 00003A77 00003A78	00 02 01			3007+ 3008+ 3009+	DC DC DC	X' 00' HL1' 2' HL1' 1'	MB used M5 used			
00003A79 00003A7A 00003A7C	00 07 00000000 00000000			3010+ 3011+ 3012+	DC DC DS	HL1' 0' HL1' 7' 2F	CC CC failed mask extracted PSW after test			
00003A84 00003A85 00003A90	FF E5C9E2E3 D9404040 00003AF4			3013+ 3014+ 3015+	DC DC DC	X' FF' CL8' VI STR' A(RE64)	extracted CC, if test fa instruction name address of v1 result	ai I ed		
00003A94 00003A98 00003A9C	00003B04 00003B14 00000010			3016+ 3017+ 3018+	DC DC DC	A(RE64+16) A(RE64+32) A(16)	address of v2 source address of v3 source result length			
00003AA0 00003AA8 00003AB0	00003AF4 00000000 00000000 0000000 00000000			3019+REA64 3020+ 3021+V1064	DC DS DS	A(RE64) FD XL16	result address gap V1 output			
00003AB8 00003AC0	00000000 00000000			3022+ 3023+*	DS	FD	gap			
00003AC8 00003AC8 00003ACC	4110 8EF8 E751 0000 0806		000010F8 00000000	3024+X64 3025+ 3026+		OF R1, V1FUDGE v21, O(R1)	load v21 fudge			
00003AD2 00003AD8 00003ADE	E310 5024 0014 E761 0000 0806 E756 0010 2C5C		00000024 00000000	3028+ 3029+	VL VISTR	R1, V2ADDR v22, O(R1) V21, V22, 2, 1	load v2 source use v21 to test decoder test instruction	n		
00003AE4 00003AE8 00003AEC	B98D 0020 5020 500C E750 5040 080E		0000000C 00003AB0	3030+ 3031+ 3032+	ST VST	R2, R0 R2, CCPSW V21, V1064	extract psw to save CC save v1 output			
00003AF2 00003AF4 00003AF4	07FB			3033+ 3034+RE64 3035+	BR DC DROP	R11 OF R5	return V1 for this test	į		
00003AF4 00003AFC 00003B04	00000000 00000000 00000000 BBBBBBBB			3036 3037	DC DC		00000000 00000000 00000000' BBBBBBBB CCCCCCC DDDDDDDD'	v1 v2		
00003B0C										

R1, V2ADDR

v22, 0(R1)

load v2 source

use v21 to test decoder

LGF

00003CCA

00003CD0

E310 5024 0014

E761 0000 0806

00000024

0000000

3142+

3143+

3194+T69

DC

A(X69)

address of test routine

00003E10

00003DB8

DS

DS

FD

XL16

gap V1 output

3246+

3247+V1070

00003E98

00003EA0

0000000 00000000

3298+RE71

3299 +

DC

DROP

0F

R5

V1 for this test

00003F8C

00003F8C

	0. 7. 0 27	ector-e7-0	o-rina (2v	ector E7 v	RR-a instructi	OII)		14 Feb 2025 21: 40: 22 Page	7
LOC	OBJECT	CODE	ADDR1	ADDR2	STMT				
	8888888 8888888				3300	DC	XL16' 88888888	8888888 8888888 00000000' v1	
	8888888 8888888				3301	DC	XL16' 88888888	8888888 8888888 00008888' v2	
					3302	11DD 4	TIT CITIES 4 4 0		
O O O E D O					3303		VISTR, 1, 1, 0		
0003FB0			000000000		3304+	DS	OFD		
0003FB0	00004000		00003FB0		3305+	USING		base for test data and test routine	
0003FB0	00004008				3306+T72	DC	A(X72)	address of test routine	
003FB4	0048				3307+	DC	H' 72'	test number	
0003FB6	00				3308+	DC	X' 00'	MD 1	
	01				3309+	DC	III.1'1'	MB used	
	01				3310+	DC	HL1' 1'	M5 used	
0003FB9	00				3311+	DC	HL1' 0'	CC	
0003FBA	07	0000000			3312+	DC	HL1'7'	CC failed mask	
0003FBC	00000000	UUUUUUUU			3313+	DS	2F	extracted PSW after test (has CC)	
003FC4	FF	DO 40 40 40			3314+	DC	X' FF'	extracted CC, if test failed	
	E5C9E2E3	D9404040			3315+	DC	CL8' VISTR'	instruction name	
	00004034				3316+	DC	A(RE72)	address of v1 result	
003FD4	00004044				3317+	DC	A(RE72+16)	address of v2 source	
	00004054				3318+	DC	A(RE72+32)	address of v3 source	
003FDC	00000010				3319+	DC	A(16)	result length	
003FE0	00004034				3320+REA72	DC	A(RE72)	result address	
003FE8	00000000				3321+	DS	FD	gap V1 output	
003FF0	0000000				3322+V1072	DS	XL16	V1 output	
003FF8	0000000								
0004000	0000000	0000000			3323+	DS	FD	gap	
					3324+*				
0004008					3325+X72	DS	0F		
0004008	4110 8EF8			000010F8	3326+	LA	R1, V1FUDGE	load v21 fudge	
	E751 0000			00000000	3327+	VL_	v21, 0(R1)		
	E310 5024			00000024	3328+	LGF	R1, V2ADDR	load v2 source	
	E761 0000			00000000			v22, 0(R1)	use v21 to test decoder	
	E756 0010				3330+		V21, V22, 1, 1	test instruction	
	B98D 0020				3331+		R2, R0	extract psw	
	5020 500C			000000C	3332+	ST	R2, CCPSW	to save CC	
	E750 5040	080E		00003FF0	3333+	VST	V21, V1072	save v1 output	
	07FB				3334+	BR	R11	return	
004034					3335+ RE72	DC	0F	V1 for this test	
004034					3336+		R5		
	8888888				3337	DC	XL16' 8888888	00000000 00000000 00000000' v1	
	0000000								
	8888888				3338	DC	XL16' 88888888	00008888 88888888 88888888' v2	
)00404C	8888888	88888888			0000				
					3339		TIT CITIES 4 4 5		
2004075					3340		VISTR, 1, 1, 0		
0004058			00001070		3341+	DS	OFD		
0004058	00004070		00004058		3342+	USING		base for test data and test routine	
	000040B0				3343+T73	DC	A(X73)	address of test routine	
000405C	0049				3344+	DC	H' 73'	test number	
	00				3345+	DC	X' 00'	·	
)00405F	01				3346+	DC	肛1'1'	MB used	
	01				3347+	DC	HL1' 1'	M5 used	
0004061	00				3348+	DC	HL1' 0'	CC	
0004061 0004062					3348+ 3349+ 3350+	DC DC DS	HL1'0' HL1'7' 2F	CC CC failed mask extracted PSW after test (has CC)	

LA

VL

LGF

R1, V1FUDGE

v21, 0(R1)

R1, V2ADDR

load v21 fudge

load v2 source

000010F8

00000000

00000024

3400+

3401+

3402+

00004158

00004162

4110 8EF8

E310 5024 0014

0000415C E751 0000 0806

LOC	OBJECT CODE	ADDR1	ADDR2	STM					
000424C 0004250	00000000 0000000			3454 3455 3456	DC DC	F' 0' F' 0'	END OF TABLE		

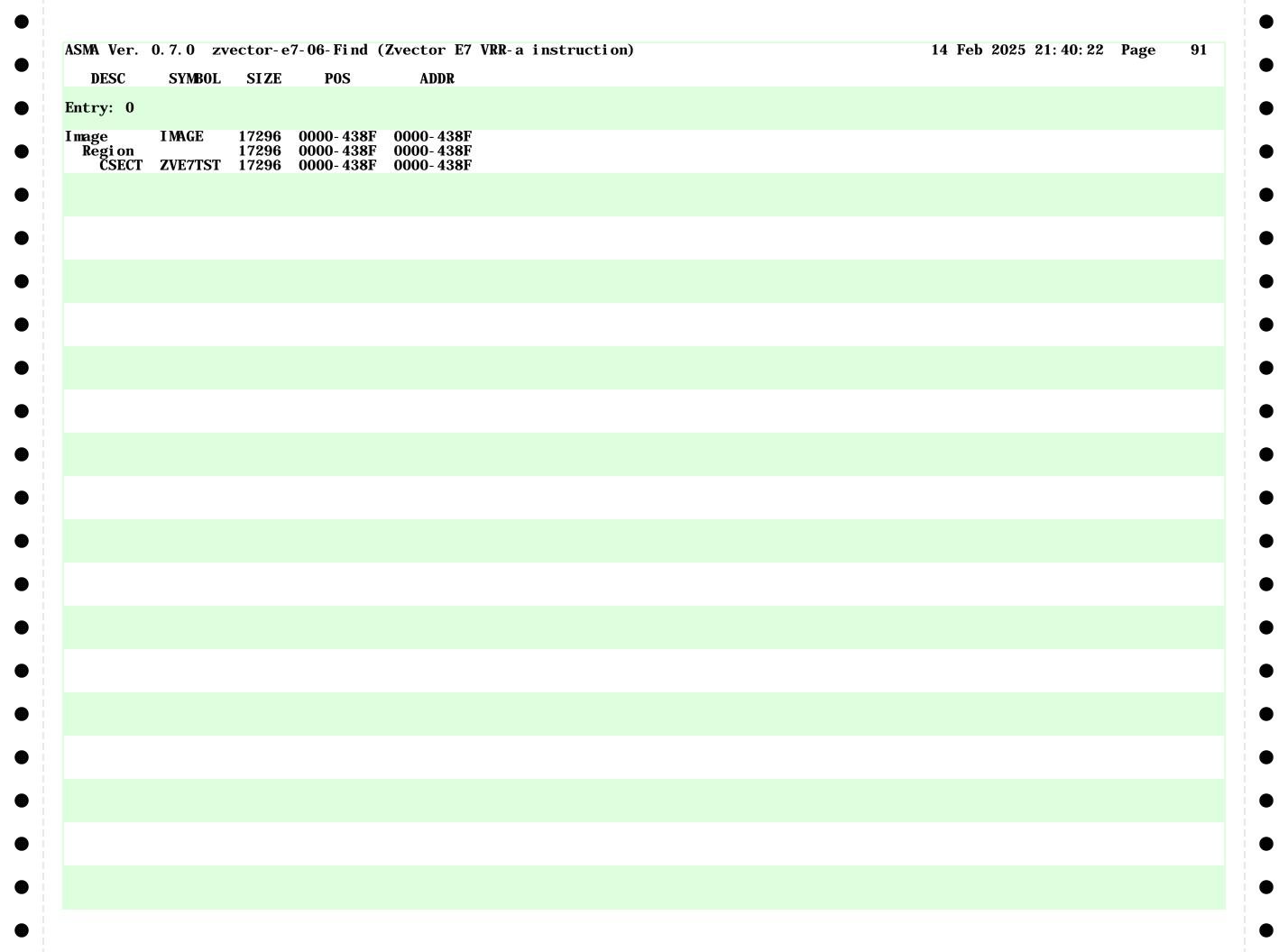
ASMA Ver.	0. 7. 0 zvector- e7-	06-Find (Zv	ector E7 V	RR-a instruc	ti on)	14 Feb 2025 21: 40: 22 Pag	e 77
LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
				3546 ****** 3547 * 3548 *****	Regis	**************************************	
		00000000 00000001 00000002 00000003 00000005 00000006 00000007 00000008 00000009 0000000A 0000000B 0000000C 0000000D 0000000E 0000000F	00000001 00000001 00000001 00000001 000000	3550 R0 3551 R1 3552 R2 3553 R3 3554 R4 3555 R5 3556 R6 3557 R7 3558 R8 3559 R9 3560 R10 3561 R11 3562 R12 3563 R13 3564 R14 3565 R15	EQU	0 1 2 3 4 5 6 7 8 9 10 11 12 13 14	
				3567 ***** 3568 * 3569 *****		**************************************	
		0000000 00000001 00000002 00000003 00000005 00000006 00000007 00000008 00000009 00000008 0000000B	00000001 00000001 00000001 00000001 000000	3571 V0 3572 V1 3573 V2 3574 V3 3575 V4 3576 V5 3577 V6 3578 V7 3579 V8 3580 V9 3581 V10 3582 V11 3583 V12	EQU	0 1 2 3 4 5 6 7 8 9 10 11	
		000000C 000000D 0000000E 00000010 00000011 00000012 00000013 00000014	0000001 00000001 00000001 00000001 000000	3584 V13 3585 V14 3586 V15 3587 V16 3588 V17 3589 V18 3590 V19 3591 V20 3592 V21	EQU EQU EQU EQU EQU EQU EQU EQU	12 13 14 15 16 17 18 19 20 21	

vii vei.	0. 7. 0 zvector- e7	00 11Ha (2)	cccor Er (www a moerae	er on,		14 Feb 2025 21:40:22	rage	78
LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
		00000016 00000017	00000001 00000001	3593 V22 3594 V23	EQU EQU	22 23 24			
		00000018 00000019 0000001A	00000001	3596 V25 3597 V26	EQU EQU EQU	25 26			
		0000001B 0000001C 0000001D	00000001 00000001 00000001	3598 V27 3599 V28 3600 V29	EĞU EĞU EĞU EĞU EĞU EĞU	27 28 29 30			
		000001E 0000001F	00000001	3601 V30 3602 V31	EQU EQU	30 31			
				3603 3604	END				

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFER	ENCES											
							1.40	1.40									
EGI N C	I	00000200 00000009	2	151	117	147	148	149									
CFOUND	U		1	512	262	269											
	X	00000014	1	518	249	209											
CMASK CMSC	U	0000000A	1	513	219												
CMSG	U	0000031C	<u> </u>	236	231												
CPRTEXP	C	00001098	1	477	266												
CPRTGOT	C	000010A8	1	480	273	070											
CPRTLI NE	C	00001055	16	472	482	276											
CPRTLNG	U	00000055	1	482	275												
CPRTNAME	C	00001082	8	475	259												
CPRTNUM	C	00001065	3	473	257	004	~~4	~~~	~~~	000	0~0	000	~ 4 =	000	4000	4000	400=
CPSW	F	000000C	4	517	246	684	721	758	796	833	870	908	945	982	1023	1060	1097
					1134	1171	1208	1245	1282	1319	1356	1393	1430	1467	1504	1541	1578
					1616	1653	1690	1727	1764	1801	1838	1875	1912	1950	1987	2024	2061
					2098	2140	2177	2214	2251	2288	2325	2362	2399	2436	2473	2510	2547
					2584	2621	2660	2697	2734	2771	2808	2845	2882	2920	2957	2994	3031
					3072	3109	3146	3183	3220	3257	3295	3332	3369	3406	3446		
TLRO	F	00000554	4	415	161	162	163	164									
ECNUM	C	000010D6	16	492	254	256	263	265	270	272	292	294	301	303	308	310	
7TEST	4	00000000	88	506	210												
7TESTS	F	00004254	4	3461	203												
DIT	X	000010AA	18	487	255	264	271	293	302	309							
NDTEST	U	00000428	1	330	208												
0 J	I	00000538	4	405	196	333											
OJPSW	D	00000528	8	403	405												
AILCONT	U	00000418	1	320													
AI LED	F	00001000	4	445	280	322	331										
AI LMSG	Ū	000003B0	1	290	226	0.2.2											
AILPSW	Ď	00000540	8	407	409												
AILTEST	ī	00000550	4	409	334												
B0001	Ē	00000280	8	180	184	185	187										
MAGE	1	00000000	17296	0	101	100	107										
MAUL	Ü	0000000	17250	429	430	431	432										
64	Ü	00010000	1	431	430	431	402										
B	TI	00010007	1	510	300												
	U TI		1			207											
5 n	U	00000008	1	511	240	307											
B	Ų	00100000	1	432	105	0.40											
SG	I	00000470	4	365	195	348											
SGCMD	C	000004BE	9	395	378	379	070										
SGMSG	Ç	000004C7	95	396	372	393	370										
SGM/C	Ī	000004B8	6	393	376												
SGOK	Ţ	00000486	2	374	371	00-											
SGRET	Ī	000004A6	4	389	382	385											
SGSAVE	F	000004AC	4	392	368	389											
EXTE7	Ŭ	000002D4	1	205	229	325											
PNAME	C	00000015	8	520	259	297											
AGE	U	00001000	1	430													
RT3	C	000010C0	18	490	255	256	257	264	265	266	271	272	273	293	294	295	302
					303	304	309	310	311								
RTLINE	C	00001008	16	454	464	314											
RTLNG	U	000004D	1	464	313												
RTMB	Č	00001044	$\ddot{3}$	459	304												
RTM5	$ar{\mathbf{C}}$	00001051	3	462	311												
RTNAME	č	00001033	8	457	297												
KINAWE.																	
RTNUM	č	00001018	3	455	295												

ASMA Ver. 0.7.0	zvector	- e7- 06- Fi nd	(Zvector	E7 VRR-	a instr	uctio	n)						14 Feb	2025	21: 40:	22 Pa	ge	80
SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERE	NCES												
					313 757 1244	321 795 1281	322 832 1318	347 869 1355	349 907 1392	365 944 1429	368 981 1466	370 1022 1503	372 1059 1540	374 1096 1577	389 1133 1615	683 1170 1652	720 1207 1689	
					1726 2213	1763 2250	1800 2287	1837 2324	1874 2361	1911 2398	1949 2435	1986 2472	2023 2509	2060 2546	2097 2583	2139 2620	2176 2659	
R1	U	0000001	1	3551		2733 3219 219	2770 3256 220	2807 3294 221	2844 3331 224	2881 3368 225	2919 3405 240	2956 3445 241	2993 246	3030 247	3071 248	3108 249	3145 276	
					314 752 865	331 753 866	332 754 867	379 755 902	393 790 903	678 791 904	679 792 905	680 793 939	681 827 940	715 828 941	716 829 942	717 830 976	718 864 977	
					978 1094	979 1128	1017 1129	1018 1130	1019 1131	1020 1165	1054 1166	1055 1167	1056 1168	1057 1202	1091 1203	1092 1204	1093 1205	
					1351	1240 1352 1464	1241 1353 1498	1242 1387 1499	1276 1388 1500	1277 1389 1501	1278 1390 1535	1279 1424 1536	1313 1425 1537	1314 1426 1538	1315 1427 1572	1316 1461 1573	1350 1462 1574	
					1575 1721	1610 1722	1611 1723	1612 1724	1613 1758	1647 1759	1648 1760	1649 1761	1650 1795	1684 1796	1685 1797	1686 1798	1687 1832	
					1946	1834 1947 2092	1835 1981 2093	1869 1982 2094	1870 1983 2095	1871 1984 2134	1872 2018 2135	1906 2019 2136	1907 2020 2137	1908 2021 2171	1909 2055 2172	1944 2056 2173	1945 2057 2174	
					2208 2320	2209 2321	2210 2322	2211 2356	2245 2357	2246 2358	2247 2359	2248 2393	2282 2394	2283 2395	2284 2396	2285 2430	2319 2431	
					2544	2433 2578 2692	2467 2579 2693	2468 2580 2694	2469 2581 2728	2470 2615 2729	2504 2616 2730	2505 2617 2731	2506 2618 2765	2507 2654 2766	2541 2655 2767	2542 2656 2768	2543 2657 2802	
					2803 2916	2804 2917 3066	2805 2951 3067	2839 2952 3068	2840 2953 3069	2841 2954 3103	2842 2988 3104	2876 2989 3105	2877 2990 3106	2878 2991 3140	2879 3025 3141	2914 3026 3142	2915 3027 3143	
					3177 3290	3178 3291	3179 3292	3180 3326	3214 3327	3215 3328	3216 3329	3217 3363	3251 3364	3252 3365	3253 3366	3254 3400	3289 3401	
R10 R11	U U	0000000A 0000000B	1 1	3560 3561	149 216	3403 158 217	3440 159 686	723	760	3443 798	835	872	910	947	984	1025	1062	
					1580	1136 1618 2100	1173 1655 2142	1210 1692 2179	1247 1729 2216	1284 1766 2253	1321 1803 2290	1358 1840 2327	1395 1877 2364	1432 1914 2401	1469 1952 2438	1506 1989 2475	1543 2026 2512	
R12	U	000000C	1	3562		2586 3074 206	2623 3111 228	2662 3148 324	2699 3185	2736 3222	2773 3259	2810 3297	2847 3334	2884 3371	2922 3408	2959 3448	2996	
R13 R14	U U	0000000D 000000E	1	3563 3564					050									
R15 R2	U U	0000000F 00000002	1	3565 3552	277 195 301	315 253 306	342 254 307	352 261 308	353 262 347	263 348	268 349	269 366	270 368	291 374	292 375	299 376	300 378	
					384 869	389 870 1133	390 907 1134	683 908 1170	684 944 1171	720 945 1207	721 981 1208	757 982 1244	758 1022 1245	795 1023 1281	796 1059 1282	832 1060 1318	833 1096 1319	
					1355 1578	1356 1615	1392 1616	1393 1652	1429 1653	1430 1689	1466 1690	1467 1726	1503 1727	1504 1763	1540 1764	1541 1800	1577 1801	
					2061	1838 2097 2325	1874 2098 2361	1875 2139 2362	1911 2140 2398	1912 2176 2399	1949 2177 2435	1950 2213 2436	1986 2214 2472	1987 2250 2473	2023 2251 2509	2024 2287 2510	2060 2288 2546	
					2547 2807	2583 2808 3071	2584 2844 3072	2620 2845 3108	2621 2881 3109	2659 2882 3145	2660 2919 3146	2696 2920 3182	2697 2956 3183	2733 2957 3219	2734 2993 3220	2770 2994 3256	2771 3030 3257	

		REFEREN	ICES															
HECK TABLE R_A	63 611 546	170 3462 655 1290 1921 2555 3191	692 1327 1958 2592 3228	729 1364 1995 2631 3266	767 1401 2032 2668 3303	804 1438 2069 2705 3340	841 1475 2111 2742 3377	879 1512 2148 2779 3417	916 1549 2185 2816	953 1587 2222 2853	994 1624 2259 2891	1031 1661 2296 2928	1068 1698 2333 2965	1105 1735 2370 3002	1142 1772 2407 3043	1179 1809 2444 3080	1216 1846 2481 3117	1253 1883 2518 3154



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ST	TT FILE NAME			
1	/home/tn529/sharedvfp/tests/zvector-e7-08-VISTR.asm			
** NO	ERRORS FOUND **			